



23<sup>rd</sup> Workshop on Radiation Imaging Detectors - iWoRID 2022  
Riva del Garda, Italy, 26 – 30 June 2022



# Semiconductor Drift Detectors: history, present and future

Giuseppe Bertuccio

Politecnico di Milano

Department of Electronic, Information and Bioengineering  
and

National Institute of Nuclear Physics (INFN)  
Milan, Italy



iWoRiD 2022

# 23rd International Workshop on Radiation Imaging Detectors

26–30 June 2022

Riva del Garda, Italy

# Thank you!

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**Cinzia Da Via**, University of Manchester, United Kingdom

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**Ralf Hendrik Menk**, Elettra Sincrotrone, Italy

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**Seppo Nenonen**, Oxford Instruments Technologies Oy, Finland

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**Nicola Massari**, Fondazione Bruno Kessler

**Giovanni Paternoster**, Fondazione Bruno Kessler

**Roberto Iuppa**, University of Trento

# Preface

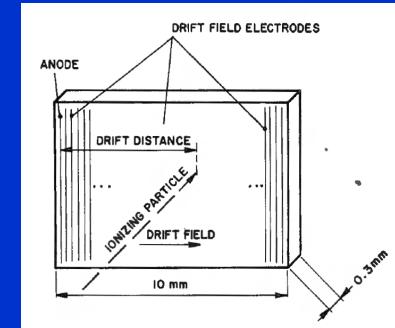


## 2022...a significant year for Silicon Drift Detectors (SDDs)

Twofold anniversary

100<sup>th</sup> of *Emilio Gatti* birthday (1922)

40<sup>th</sup> of SDD's conception (1982)



# Outline



## Semiconductor Drift Detectors

### ➤ History

- the context
- conception and evolution

### ➤ Present

- state of the art
- running R&D

### ➤ Future

- Where SDDs can go
- What we could expect

# History of SDD

## ...a preface...

# Historical overview ?

Historical aspects  
in Science and Technology (S&T)  
are generally neglected

(Psychological) reasons:

- Old is outdated
- New makes Old obsolete
- S&T look at the future, past doesn't care

Drawback of the above vision:

- The time-dimension of S&T is lost
- S&T become anonymous



Actually...S&T is made by women and men in an historical context!

# What History in S&T can offer us...



To grow a consciousness on:

- How discoveries or ideation were born...and can born
- How much new devices improve from the first prototypes!



In addition...

to know men and women who have allowed  
the current scientific context

- ...is fascinating
- ...young Researchers can acquire  
confidence and motivation in their work



it would be great if every conference had a historical talk!

# The birth of the Semiconductor Drift Detectors

# 1983: the SDD concept is published

PROCEEDINGS  
OF THE  
1983 DPF WORKSHOP  
ON  
**Collider Detectors:**  
**Present Capabilities**  
**And**  
**Future Possibilities**

February 28 - March 4, 1983

Lawrence Berkeley Laboratory  
University of California  
Berkeley, California 94720

## THE CONCEPT OF A SOLID STATE DRIFT CHAMBER\*

E. Gatti†, and P. Rehak

Brookhaven National Laboratory  
Upton, New York 11973



# Pavel Rehak



1945 - 2009

1969	Ph.D. in natural sciences, University of Prague, Czechoslovakia
1972	2 <sup>nd</sup> Ph.D. in high-energy physics, Scuola Normale Superiore, Pisa, Italy
1973	Kernforschungszentrum, Karlsruhe, Germany
1975	Yale University and CERN
1976	Brookhaven National Laboratory, Physics Department
1994	Brookhaven National Laboratory, Instrumentation Division

# Emilio Gatti



1922 - 2016

1946	Industrial Electrical Engineering, University of Padua, Italy
1946 - '48	Electrical Communication specialization, Galileo Ferraris Institute, Turin, Italy
1948 - '57	C.I.S.E (Nuclear Science Research Centre), Milan, Italy
1951 - '97	Politecnico di Milano, professor of Physics, professor of Electronics
1998 - 2016	Politecnico di Milano Emeritus professor

# Emilio Gatti: main inventions and contribution



1922 - 2016

- 1953 Added step method for single channel discriminators
- 1955 Charge Sensitive Preamplifier
- 1956 Vernier method to improve the event timing
- 1962 Optimum filters for radiation detectors
- 1962 Spectrum expander
- 1963 The Light Chamber
- 1963 Sliding scale method for A/D Conversion
- 1964 Statistical theory of scintillation counters
- 1983 The Solid State Drift Detector

# E. Gatti ideas on Mars planet exploration

## Alpha Particle X-ray Spectrometer (APXS)

- Silicon Drift Detector
- Charge Sensitive Preamplifier
- Sliding Scale ADC



# Emilio Gatti - awards



1922 - 2016

1953	Bianchi Prize – Italian Electrical Engineering Society
1968	National Prize for Physics – Angelo della Riccia Foundation
1971	Richi Prize – Italian Electrical and Electronic Engineering Society
1972	Gold Medal for School, Culture and Art – President of the Republic
1973	Fellow of IEEE
1982	Publication Prize - Italian Electrical Engineering Society
1984	IEEE Centennial Medal
1988	Annual Merit Award - Nuclear & Plasma Sciences Society
1995	Laurea Honoris Causa in Physics – University of Milan
1996	International Prize Gerolamo Cardano – Rotary and University of Pavia
2003	IEEE Radiation Instrumentation Outstanding Achievement Award

# 1983: the concept published

PROCEEDINGS  
OF THE  
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ON

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THE CONCEPT OF A SOLID STATE DRIFT CHAMBER\*

E. Gatti†, and P. Rehak

Brookhaven National Laboratory  
Upton, New York 11973



P. Rehak

E. Gatti

# When and why an invention can born

## the case of SDD's

# from 1908 to '70: Ionisation Chambers

IONIZATION CHAMBERS AND COUNTERS

Experimental Techniques

by

BRUNO B. ROSSI

Professor of Physics, Massachusetts Institute of Technology

and

HANS H. STAUB

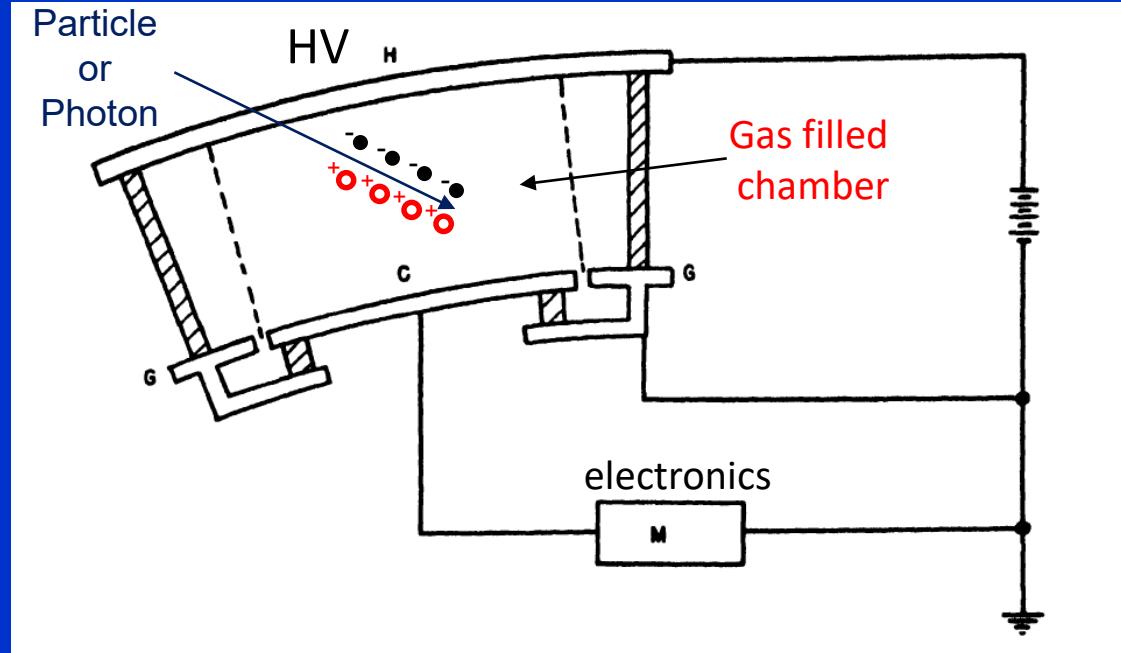
Professor of Physics, Stanford University

First Edition

New York · Toronto · London

McGRAW-HILL BOOK COMPANY, INC.

1949



POLITECNICO  
DI MILANO

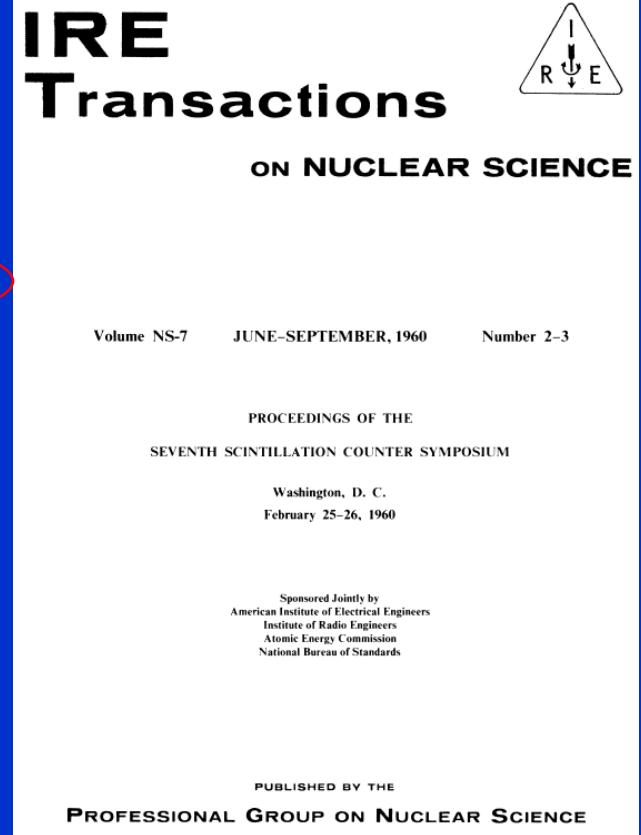
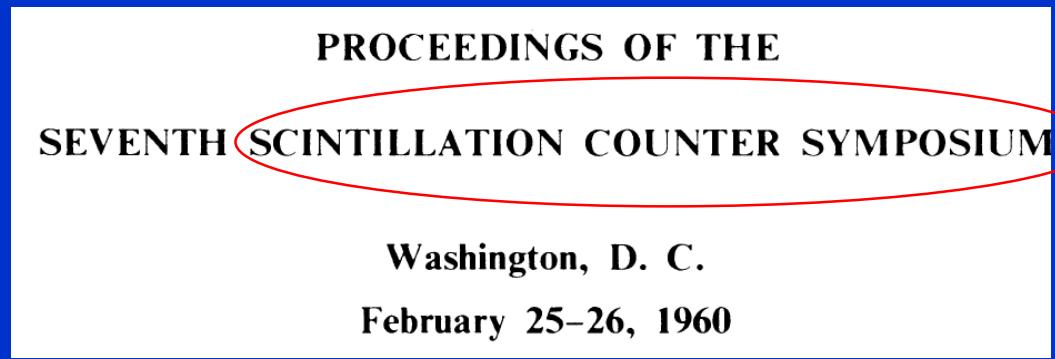
Giuseppe Bertuccio, *Semiconductor Drift Detectors: history, present and future*

23rd Workshop on Radiation Imaging Detectors - iWoRiD 2022 - Riva del Garda, Italy, 26 – 30 June 2022



slide 17

# 1960: something new appears...

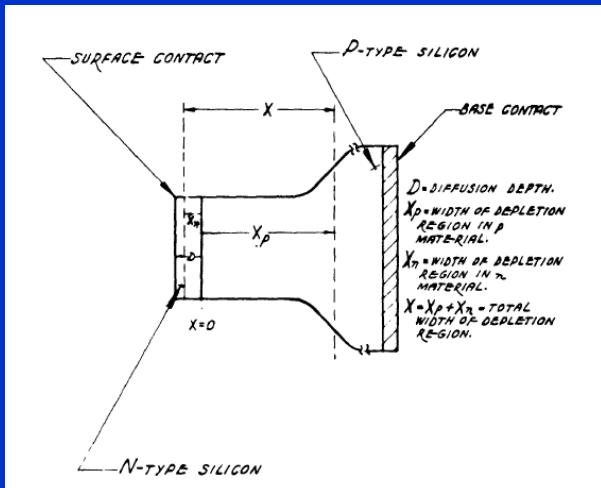


# 1960: from *gases* to *semiconductors*

## The Solid - State Ionization Chamber\*

S. S. FRIEDLAND,† J. W. MAYER,‡  
AND J. S. WIGGINS‡

†Solid State Radiations, Inc., Culver City, Calif.  
‡Hughes Aircraft Co., Los Angeles, Calif.



Diffused  
pn junction

### THE SOLID-STATE IONIZATION CHAMBER

#### The Solid - State Ionization Chamber\*

S. S. FRIEDLAND,† J. W. MAYER,‡  
AND J. S. WIGGINS‡

**Summary:** Shallow diffused silicon  $p-n$  junction detectors have been used as room-temperature particle spectrometers for protons, alpha particles, heavy ions, and fission fragments. By the use of high base resistivity devices operated at high reverse biases ( $> 200$  volts), the width of the sensitive volume has been extended beyond 0.5 mm, permitting linear response to protons up to 9 mev. Improved diffusion techniques have reduced the "dead" or non-diffused regions so that the "window effect" is reduced, increasing the low energy response to below 200 kev for alpha particles. Use of low-noise amplifiers has permitted observation of half-widths of the pulse height distribution equivalent to 18 kev.

Use of shallow diffused silicon  $p-n$  junctions as charged particle detectors has been extensively investigated at Hughes Aircraft Company and other laboratories.<sup>1</sup> As was mentioned in the preceding paper, the units can be made to respond linearly to energy lost by an ionizing particle within the sensitive volume of the junction. Essentially, the high field region within the device determines the sensitive volume of the detector, a concept which follows closely the action of a conventional ionization chamber.

A discussion of the principles of operation of a solid-state ionization chamber will be aided by referring to Fig. 1. A  $p-n$  junction is formed close to one surface of a slab of high resistivity p-type silicon by a shallow diffusion of phosphorus. A reverse bias is

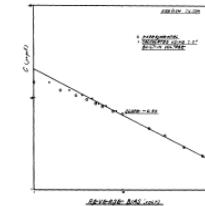


Fig. 2—Capacity vs reverse bias relation of a shallow-diffused  $p-n$  junction.

established across the junction, which in turn establishes a depletion region (space-charge region) on both sides of the junction. The width of the depletion region from the junction into the p-type material is  $X_p$ , from the junction into the n region  $X_n$ , and the total depletion width is given by  $X$  where

$$X = X_p + X_n.$$

The magnitude of  $X_n$  or  $X_p$  is given approximately by

$$X = \left( \frac{eV}{2\pi qN_i} \right)^{1/2}$$

where  $V$  is the total potential drop across the depletion region in question,  $\epsilon$  is the dielectric constant of the silicon,  $q$  is the electronic charge, and  $N_i$  is the concentration of ionized impurity centers.

In a diffused junction, as shown in Fig. 1,  $X_n/X_p = (\sigma_n/\sigma_p)^{1/2}$  may typically have a value of  $10^3$ , where  $\sigma_n$  and  $\sigma_p$  are the conductivities of the n- and p-type regions, respectively. Thus, the major portion of the depletion region exists beyond the junction into the bulk of the p-type silicon, and only a small region exists in front of the junction approaching the surface.

It can be seen from these relations that the width of the depletion region or sensitive volume of the device is proportional to  $(\mu_0 V_g)^{1/2}$  where  $\mu$  is the re-

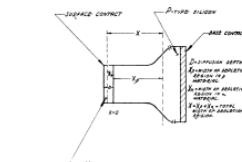
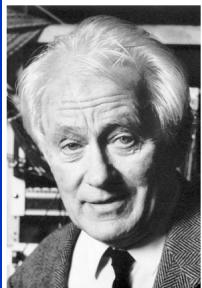


Fig. 1—Schematic diagram of a  $p-n$  junction under reverse bias.

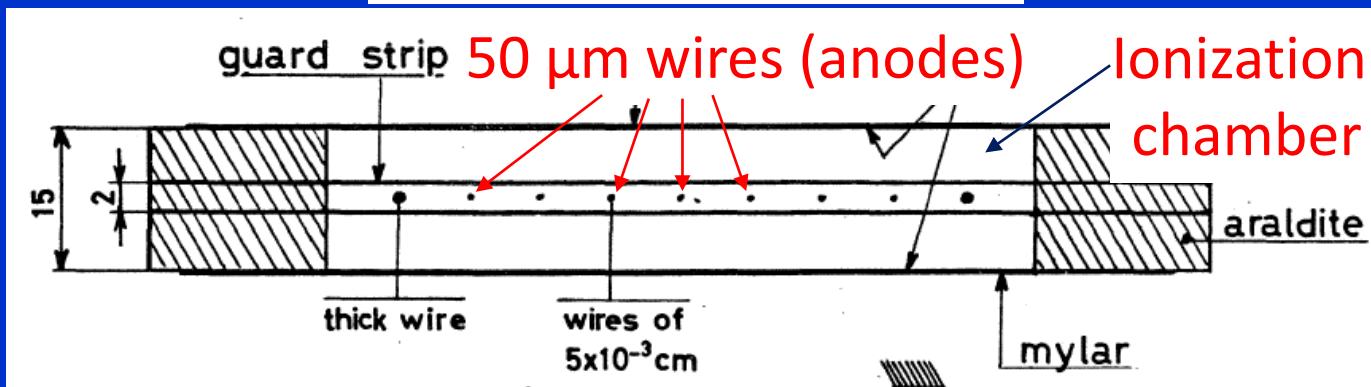
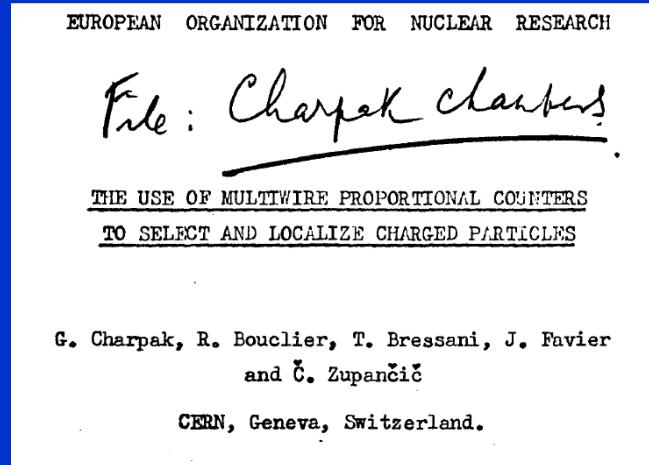
\*This work has been supported in part by the Defense Atomic Support Agency under Contract DA-49-146-XZ-016. †Solid State Radiations, Inc., Culver City, Calif. ‡Hughes Aircraft Co., Los Angeles, Calif.

<sup>1</sup>See, for example, S. S. Friedland, J. W. Mayer, and J. S. Wiggins, "Tiny semiconductor is fast, linear detector," *Nucleonics*, vol. 18, pp. 54-59; February, 1960.

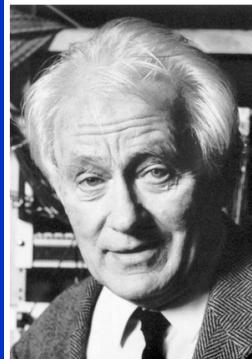
# 1968: The Multiwire Chamber



Georges Charpak  
(1924-2010)



# 1969: The (gas) Drift Chamber



Georges Charpak  
(1924-2010)

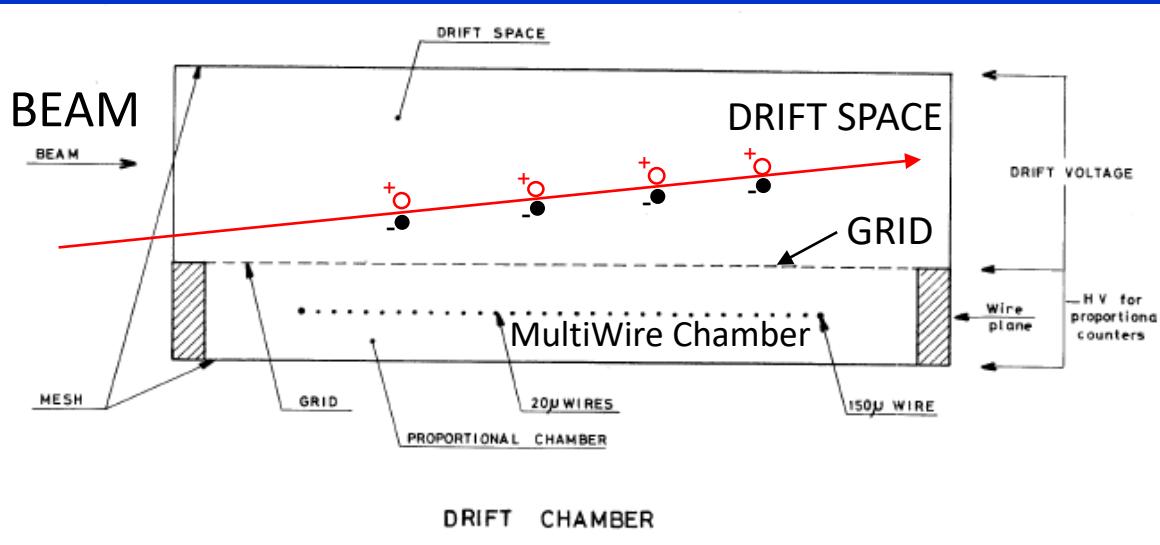
Nobel Prize  
in Physics 1992

"for his invention and development of particle detectors, in particular the multiwire proportional chamber"

## TRACK LOCALIZATION BY MEANS OF A DRIFT CHAMBER<sup>\*)</sup>

T. Bressani, G. Charpak, D. Rahm<sup>\*\*)</sup>, Č. Zupančič

CERN, Geneva, Switzerland



# BNL 1978-'81: Rehak works on ionization chambers

IEEE Transactions on Nuclear Science, Vol. NS-25, No. 1, February 1978

## SECOND COORDINATE READOUT IN DRIFT CHAMBERS BY CHARGE DIVISION\*

V. Radeka and P. Rehak  
Brookhaven National Laboratory  
Upton, New York 11973

IEEE Transactions on Nuclear Science, Vol. NS-28, No. 1, February 1981

## SIGNAL SHAPING AND TAIL CANCELLATION FOR GAS PROPORTIONAL DETECTORS AT HIGH COUNTING RATES\*

R. A. Boie, A. T. Hrisoho,<sup>†</sup> and P. Rehak

Brookhaven National Laboratory  
Upton, New York 11973



# Milano, 1978-'79: Gatti works on ionization chambers

IEEE Transactions on Nuclear Science, Vol. NS-25, No. 1, February 1978

OPTIMUM FILTERS WITH TIME WIDTH CONSTRAINTS  
FOR LIQUID ARGON TOTAL-ABSORPTION DETECTORS\*

Emilio Gatti

Istituto di Fisica Politecnico Milano  
Milano, Italy

and

Veljko Radeka

Brookhaven National Laboratory  
Upton, New York 11973

in collaboration with  
Veljko Radeka (BNL)



IEEE Transactions on Nuclear Science, Vol. NS-26, No. 2, April 1979

CONSIDERATIONS FOR THE DESIGN OF A TIME  
PROJECTION LIQUID ARGON IONIZATION CHAMBER\*

E. Gatti, G. Padovini, L. Quartapelle<sup>†</sup>

and

N. E. Greenlaw and V. Radeka<sup>#</sup>

# 1979: a Breakthrough in semiconductor detectors

NUCLEAR INSTRUMENTS AND METHODS 169 (1980) 499-502

Joseph Kemmer

Univ. Munich



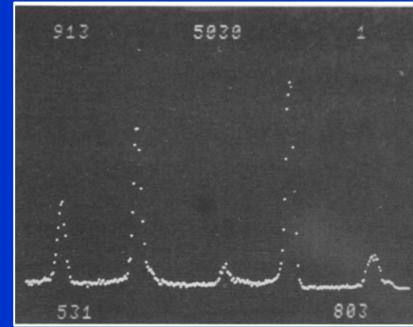
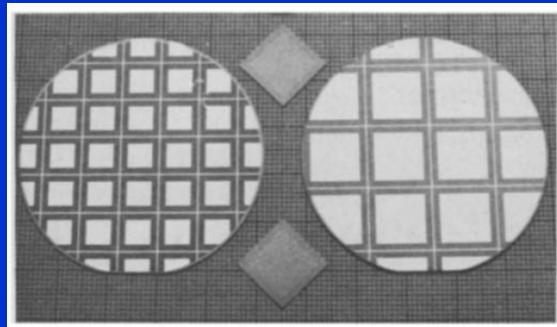
## FABRICATION OF LOW NOISE SILICON RADIATION DETECTORS BY THE PLANAR PROCESS

J KEMMER

*Fachbereich Physik der Technischen Universität München, 8046 Garching, Germany*

Received 30 July 1979 and in revised form 22 October 1979

*Dedicated to Prof Dr H -J Born on the occasion of his 70th birthday*



# 1982: first Si Microstrip Detector with planar technology

Joseph Kemmer  
Univ. Munich



Paul Burger  
Enertec company



Erik Heijne  
CERN



IEEE Transactions on Nuclear Science, Vol. NS-29, No. 1, February 1982

## PERFORMANCE AND APPLICATIONS OF PASSIVATED ION-IMPLANTED SILICON DETECTORS

J. KEMMER

Fakultät für Physik der Technischen Universität München

8046 GARCHING, Germany

P. BURGER and R. HENCK

ENERTEC-SCHLUMBERGER, 1, Parc des Tanneries

67380 STRASBOURG Lingolsheim, France

E. HEIJNE

CERN, European Organisation for Nuclear Research

1211 GENEVA 23, Switzerland

Microstrip Detector  
(first with planar technology)

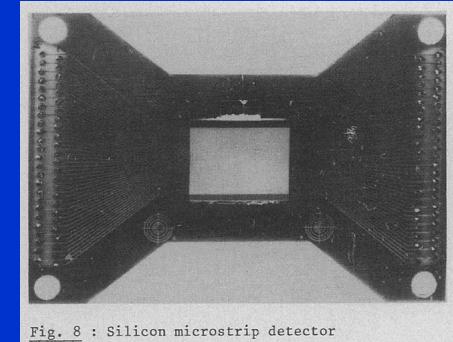


Fig. 8 : Silicon microstrip detector

It could be called  
the Solid State Multiwire Chamber

Are time and conditions ready  
for a Solid State Drift Chamber?

# 1982: Gatti and Rehak studied Efield in MCP

IEEE Transactions on Nuclear Science, Vol. NS-30, No. 1, February 1983

## Study of the Electric Field Inside Microchannel Plate Multipliers<sup>a)</sup>

E. Gatti<sup>b)</sup>, K. Obac<sup>c)</sup> and P. Rehak  
Brookhaven National Laboratory  
Upton, New York 11973



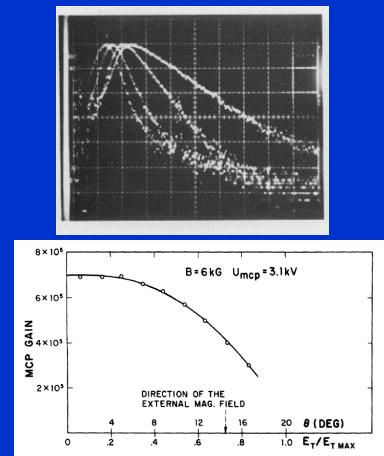
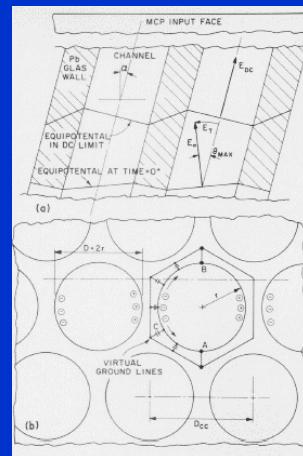
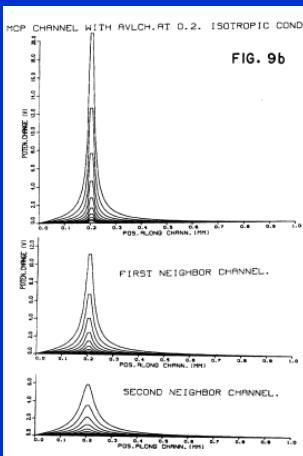
$$u(x, y, z, s) = \frac{Q_0}{4\pi\epsilon_r \sqrt{\gamma(r-r_0)^2 + (z-z_0)^2}} \frac{1}{\sqrt{1/\tau_r + s}} \frac{1}{\sqrt{b+s}} \quad (20)$$

where  $\gamma = \epsilon_z/\epsilon_r$ ;  $\tau_r = \epsilon_r/\sigma_r$ ;  $\tau_z = \epsilon_z/\sigma_z$ ;  
 $(r-r_0)^2 = (x-x_0)^2 + (y-y_0)^2$

and  $b = \frac{\gamma(r-r_0)^2/\tau_z + (z-z_0)^2/\tau_r}{\gamma(r-r_0)^2 + (z-z_0)^2}$ .

The form of equation (20) has a known Laplace inverse-transform which is:

$$U(x, y, z, t) = \frac{Q_0}{4\pi\epsilon_r \sqrt{\gamma(r-r_0)^2 + (z-z_0)^2}} \cdot \exp\left[-\frac{1}{2}(b+1/\tau_r)t\right] \cdot I_0\left(\frac{1}{2}(b-1/\tau_r)t\right) \quad (21)$$

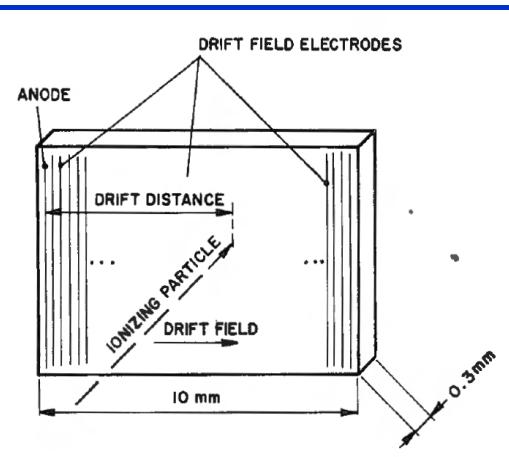


# 1983: the SSD concept published

## THE CONCEPT OF A SOLID STATE DRIFT CHAMBER\*

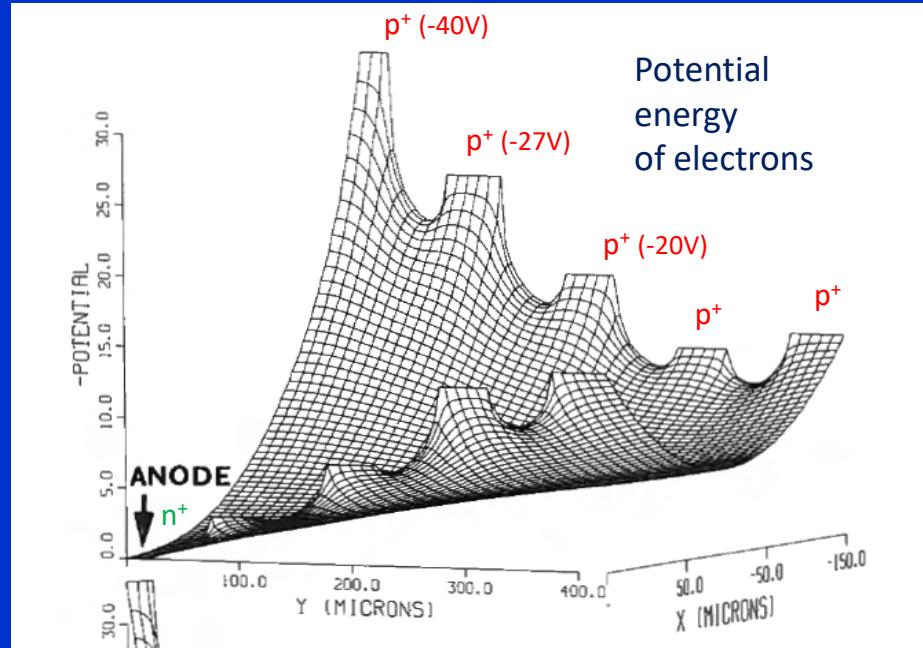
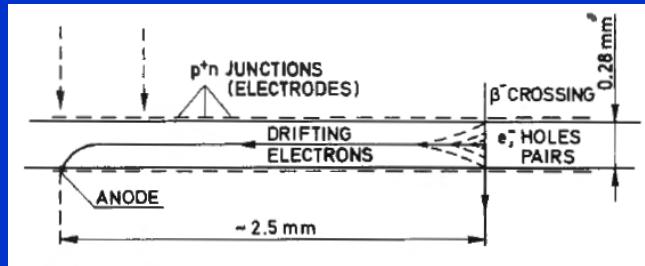
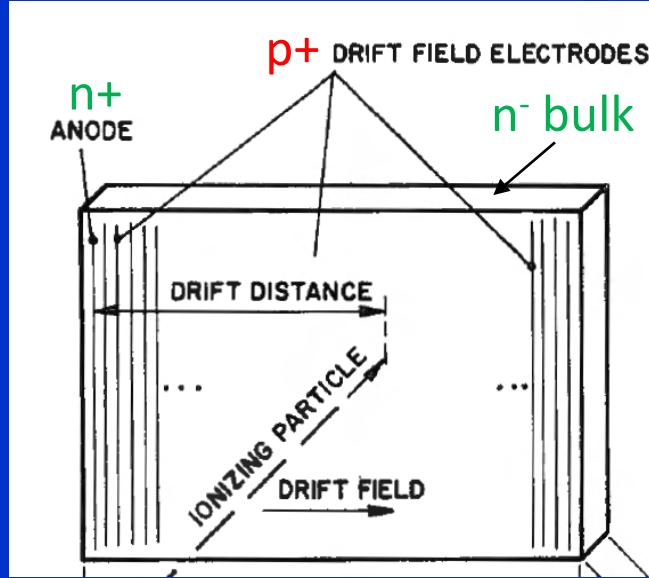
E. Gatti†, and P. Rehak

Brookhaven National Laboratory  
Upton, New York 11973



advantages w.r.t. Gas Drift Chambers:  
reduced  $\delta$ -rays  
reduced ionization density fluctuation

# SDD: principle of operation



Drift time gives a coordinate

# 1984: first SDD realized

Nuclear Instruments and Methods in Physics Research 226 (1984) 129–141

## SILICON DRIFT CHAMBERS – FIRST RESULTS AND OPTIMUM PROCESSING OF SIGNALS \*

Emilio GATTI

Dipartimento di Elettronica, Politecnico di Milano, Piazza Leonardo da Vinci 32, Milano, Italy

Pavel REHAK

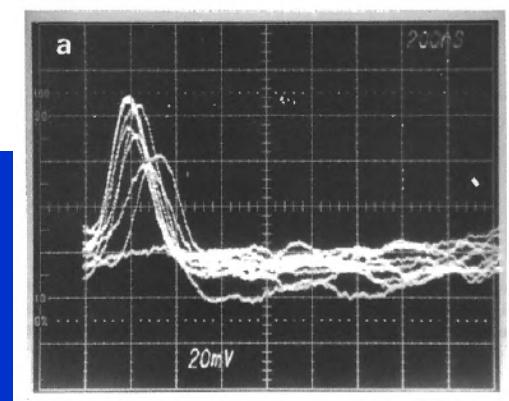
Brookhaven National Laboratory, Upton, New York 11973, USA

Jack T. WALTON

Lawrence Berkeley Laboratory, Berkeley, California 94720, USA

Fabricated at: Lawrence Berkeley Laboratory, CA, USA

Tested at: Brookhaven National Laboratory, NY, USA



# 1985: BNL, PoliMI, Univ. Munich, LBL

IEEE Transactions on Nuclear Science, Vol. NS-32, No. 2, April 1985

## SEMICONDUCTOR DRIFT CHAMBERS

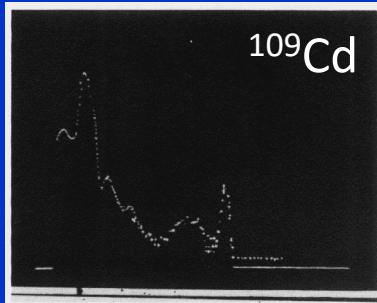
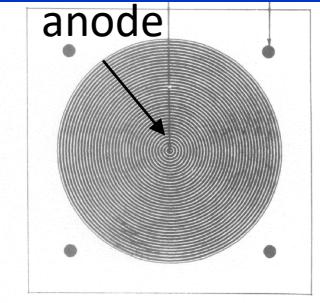
E. Gatti<sup>\*o</sup>, P. Rehak<sup>\*</sup>, A. Longoni<sup>o</sup>  
Brookhaven National Laboratory, Upton, N.Y., USA  
<sup>o</sup>Politecnico di Milano, Milano, Italy

J. Kemmer

Fakultät für Physik der Technischen Universität, München, FRG

P. Holl, R. Klanner, G. Lutz and A. Wylie  
Max Planck Institut für Physik und Astrophysik, München, FRG

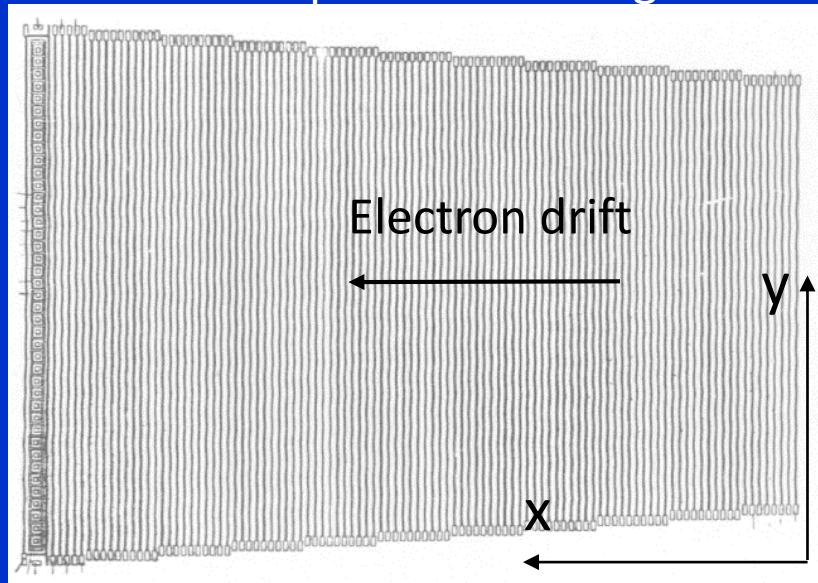
F. Goulding, P.N. Luke, N.W. Madden, J. Walton  
Lawrence Berkeley Laboratory, California, USA



Circular SDD  
for X-rays

41 anodes

## Multi-anodes SDD for 2D-position sensing



300 e- r.m.s.  
2.6 keV FWHM

# SDD in particle colliders

1995

ALICE SDD

CERN – LHC

Silicon Vertex Tracker (SVT)



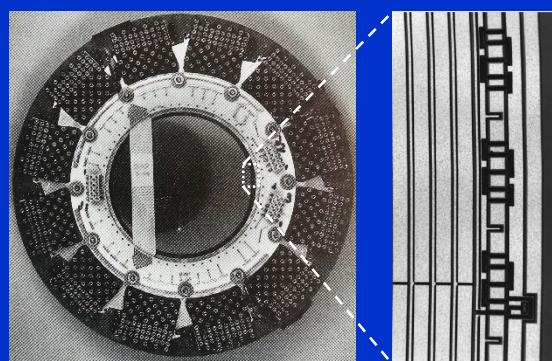
260 x 52 cm<sup>2</sup> Linear SDDs  
in 2 layers  
2 x 256 anodes/SDD

1996

AZTEC SDD

CERN – NA45/WA98

Microvertex detector



Cylindrical 55 cm<sup>2</sup> SDD  
Radial drift: 700 V/cm  
360 anodes

2001

STAR SDD

BNL – RHIC

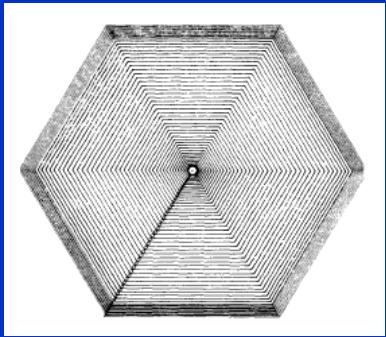
Silicon Drift Tracker (SDT)



216 x 40 cm<sup>2</sup> Linear SDDs  
in 3 Cylindrical layers  
2 x 240 anodes/SDD

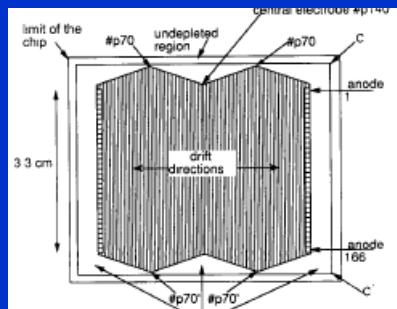
# Development of SDD's

Spiral (1989)



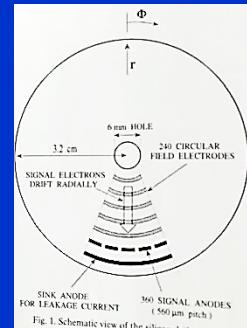
Large Area (1991)

4 x 4 cm

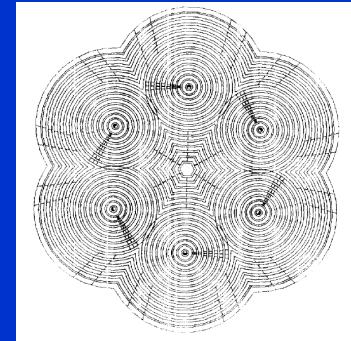


3" wafer cylindrical (1992)

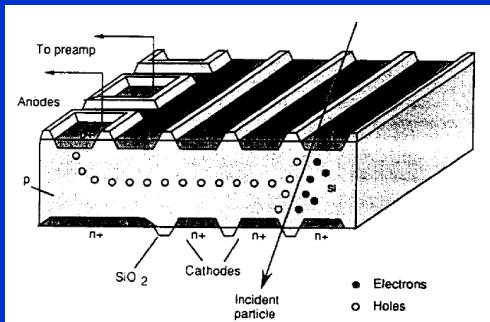
360 anodes



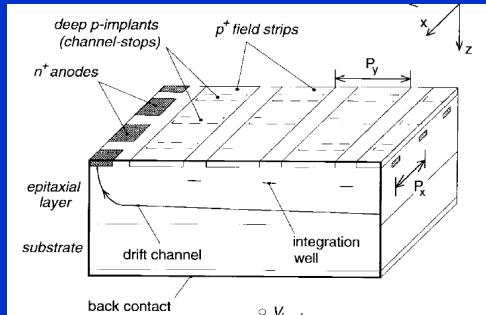
SDD Array (1994)



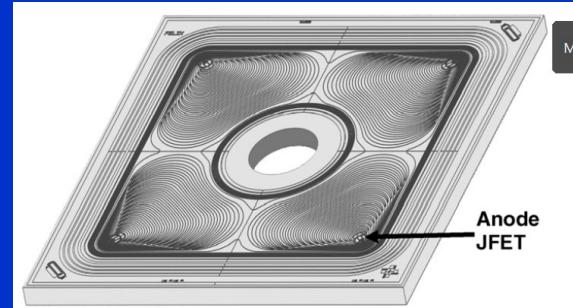
P-type SDD (1995)



Controlled Drift (1997)



Droplet SDD (2004)



# Ge and Compound SDD

1987: Ge Drift Detector

GERMANIUM DRIFT DETECTOR: A NEW TOMOGRAPHIC DEVICE PROVIDING INFORMATION ON THE CHEMICAL PROPERTIES OF A BODY SECTION\*,\*\*

Emilio GATTI<sup>+</sup> and Pavel REHAK

Brookhaven National Laboratory, Upton, NY 11973, USA

Josef KEMMER

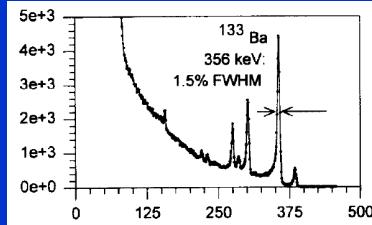
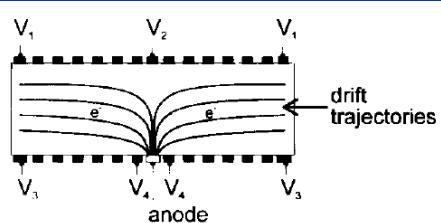
Faculty of Physics, Munich Technical University, D-8048 Garching, FRG

1996: HgI<sub>2</sub> Drift Detector

New gamma-ray detector structures for electron only charge carrier collection utilizing high-Z compound semiconductors

B.E. Patt\*, J.S. Iwanczyk, G. Vilkelis, Y.J. Wang

Xsirius, Inc., 1220-A Avenida Acaso, Camarillo, CA 93012, USA

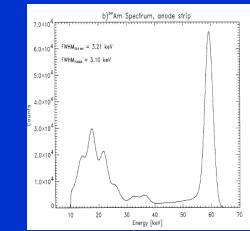
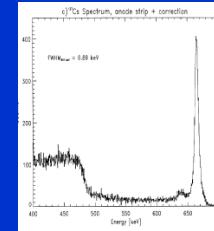
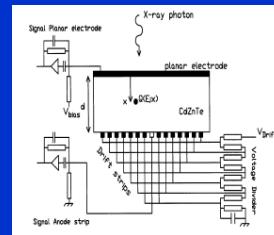


1998: CdZnTe Drift Detector

CdZnTe drift detector with correction for hole trapping

M.A.J. van Pamelen, C. Budtz-Jørgensen\*

Danish Space Research Institute, Juliane Maries Vej 30, 2100 København Ø, Denmark



A key point of Drift Detector: single charge carrier induction

# Key features of SDD's

	Planar Junction	SDD
DC output current $I_{DET}$	÷ Detector's Volume	÷ Detector's Volume
Output capacitance $C_{DET}$	÷ Detector's Area $\approx 35 \text{ pF/cm}^2$ (300 $\mu\text{m}$ thick)	Independent of Area $< 100 \text{ fF}$

$C_{IL}$  : Load capacitance at Preamp. input     $C_{IL} = C_{DET} + C_{connection} + C_{feedback/test}$

$C_G$  : Preamp. input FET capacitance

Minimum noise for capacitive matching:     $C_G = C_{IL}$

Minimum ENC:     $ENC_{min} \div (I_{DET})^n (C_{IL})^m$

Optimum shaping time:     $\tau_{opt} \div \frac{(C_{IL})^m}{(I_{DET})^n}$



Lower ENC  
@  
Shorter shaping time  
↓  
Higher resolution  
@  
Higher photon/particle rate

# Key features of SDD's

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Lower ENC  
@  
Shorter shaping time  
↓  
Higher resolution  
@  
Higher photon/particle rate

# The development of the Front-End Electronics for SDD's

# 1987-'89: JFET and Preamp. integrated

Brookhaven – Milan – Munich collaboration

JOURNAL DE PHYSIQUE  
Colloque C4, supplément au n°9, Tome 49, septembre 1988

## JFET FOR COMPLETELY DEPLETED HIGH RESISTIVITY SILICON

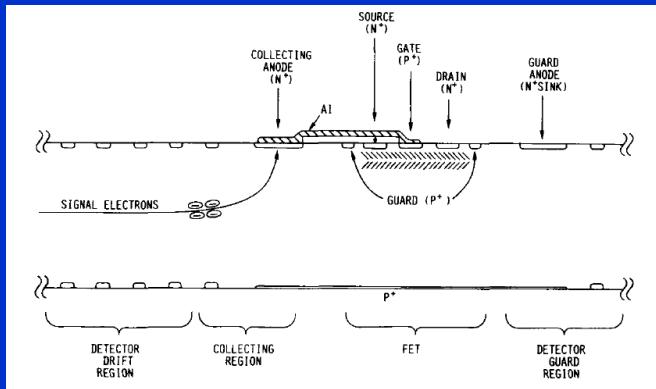
V. RADEKA, P. REHAK, S. RESCIA, E. GATTI\*, A. LONGONI\*, M. SAMPIETRO\*,  
G. BERTUCCIO\*, P. HOLL\*\*, L. STRUADER\*\* and J. KEMMER\*\*\*

IEEE ELECTRON DEVICE LETTERS, VOL. 10, NO. 2, FEBRUARY 1989

91

## Implanted Silicon JFET on Completely Depleted High-Resistivity Devices

VELJKO RADEKA, FELLOW, IEEE, PAVEL REHAK, MEMBER, IEEE, S. RESCIA, EMILIO GATTI, FELLOW, IEEE,  
A. LONGONI, M. SAMPIETRO, G. BERTUCCIO, P. HOLL, L. STRÜDER, AND J. KEMMER



## CHARGE-SENSITIVE PREAMPLIFIER FOR INTEGRATION ON SILICON RADIATION DETECTORS: FIRST EXPERIMENTAL RESULTS

P. REHAK  
S. RESCIA  
V. RADEKA

Brookhaven National Laboratory  
Upton, NY 11973, USA

E. GATTI  
A. LONGONI  
M. SAMPIETRO  
G. BERTUCCIO

Istituto di Fisica  
Politecnico di Milano  
CEQSE-CNR  
Piazza Leonardo da Vinci 32, 20133 Milano, Italy

J. KEMMER  
U. PRECHTEL  
T. ZIEMANN  
MBB GmbH  
Postfach 801149, 8000 München 80, Federal Republic of Germany

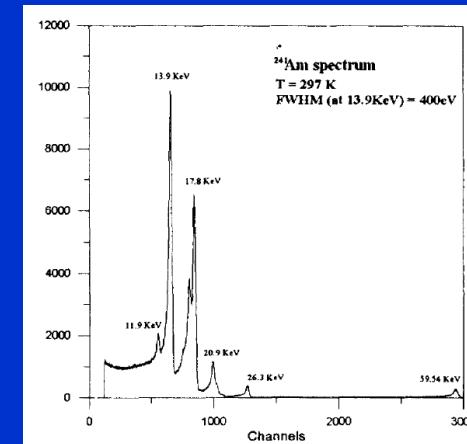
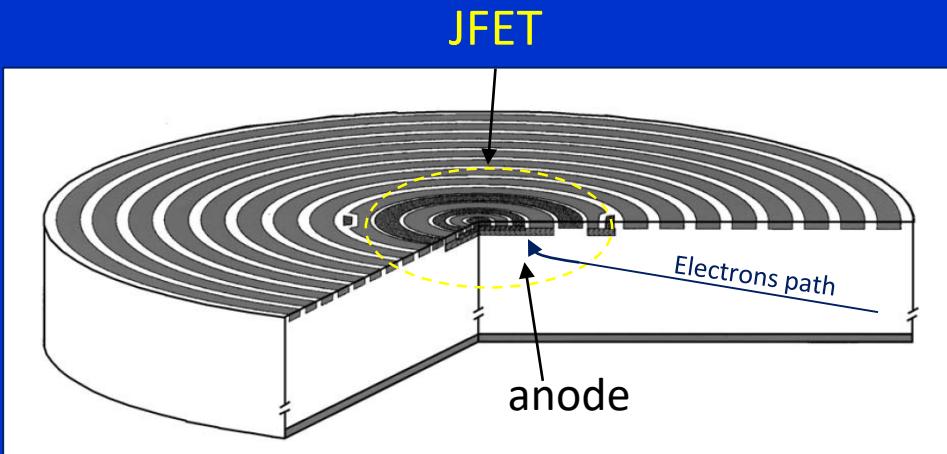
13th June 1989

# 1994: SDD with integrated JFET

**Design and test at room temperature of the first  
Silicon Drift Detector with on-chip electronics**

R. Hartmann, D. Hauff, S. Krisch, P. Lechner, G. Lutz, R. H. Richter, H. Seitz and L. Strüder  
MPI Halbleiterlabor, Paul-Gerhardt-Allee 42, 81245 München, Germany

G. Bertuccio, L. Fasoli, C. Fiorini, E. Gatti, A. Longoni, E. Pinotti and M. Sampietro  
Politecnico di Milano, Dipartimento di Elettronica e Informazione, Piazza L. da Vinci 32, 20133 Milano, Italy



SDD used area  
2 mm<sup>2</sup>

@ +24°C  
41 e- rms  
(356 eV FWHM)

Proceedings of IEDM 94-545

# 1997: SDD and CMOS preamplifier

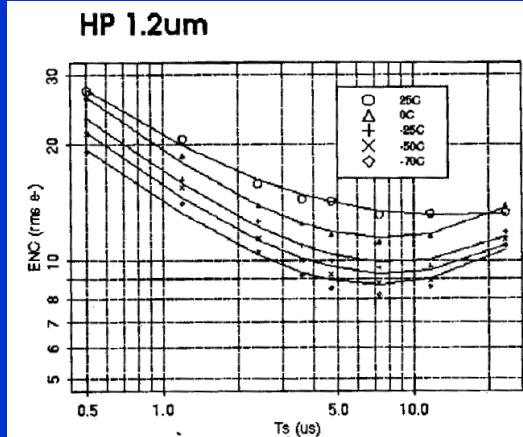
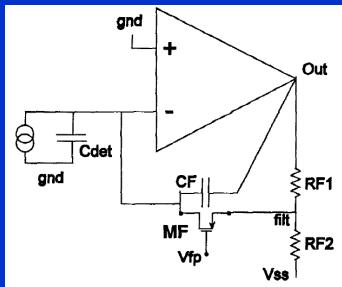
CMOS Preamplifier with High Linearity and Ultra Low Noise for X-Ray Spectroscopy

P. O'Connor\*, P. Rehak\*, G. Gramegna<sup>†</sup>, F. Corsi<sup>†</sup>, C. Marzocca<sup>†</sup>

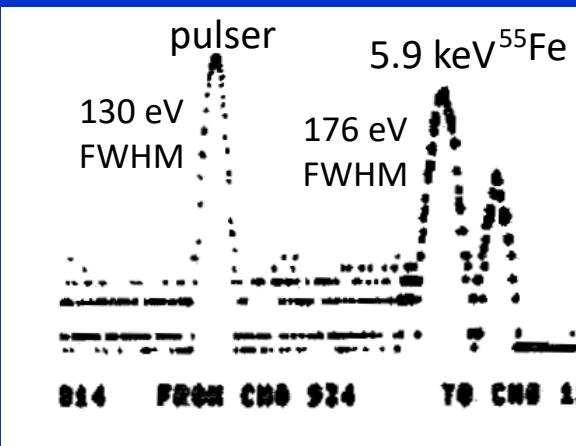
\* Brookhaven National Laboratory, Upton, NY 11973 USA

<sup>†</sup>Politecnico di Bari, Dipartimento di Elettrotecnica ed Elettronica, via E. Orabona 4, 70125 Bari, Italy

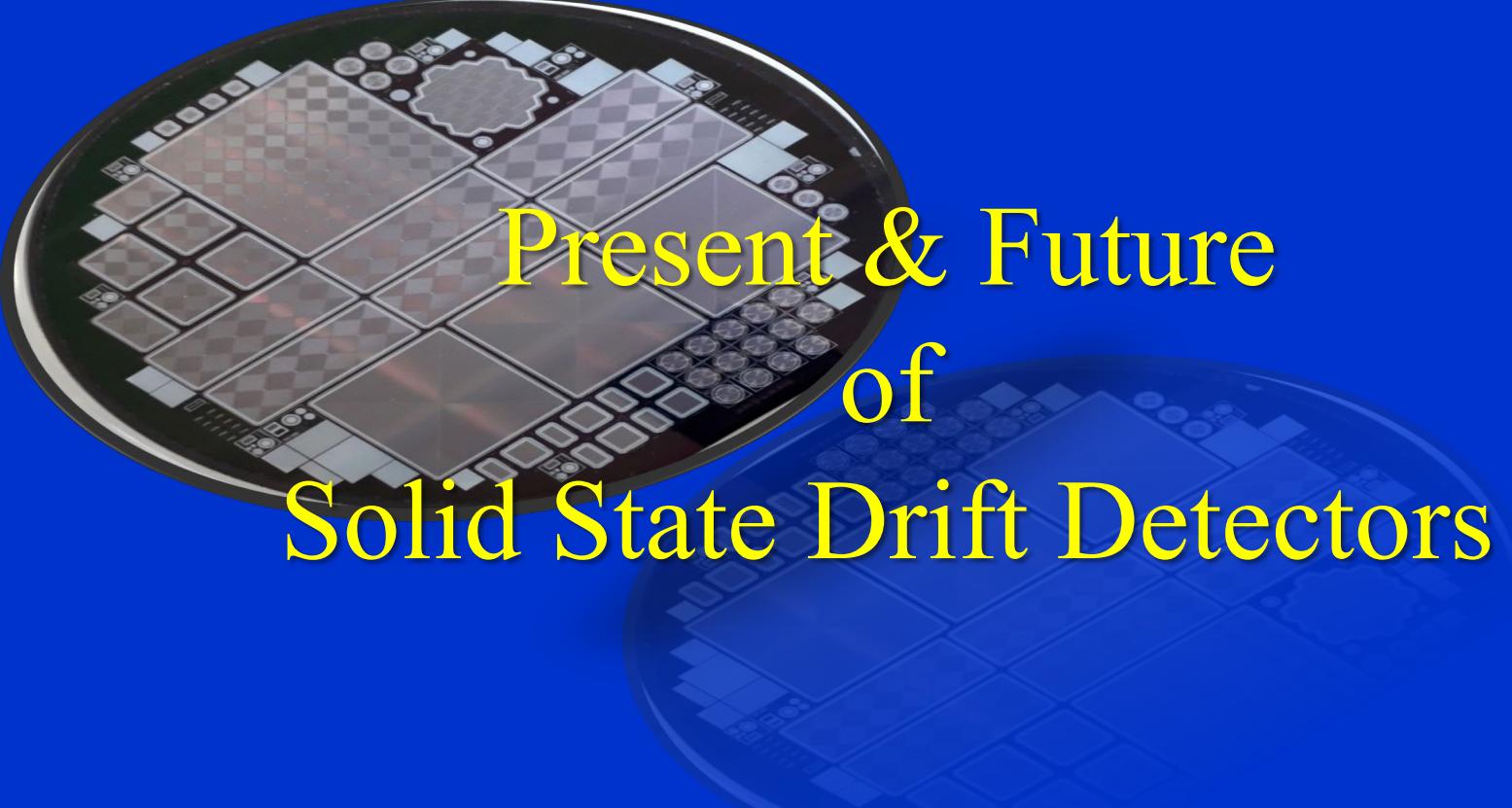
HP CMOS 1.2  $\mu$ m  
AMS CMOS 1.2 $\mu$ m



Intrinsic ENC = 9 e- rms  
@ +25°C



With SDD: ENC = 16 e- rms  
@ -70°C



# Present & Future of Solid State Drift Detectors

# Present: many commercial SDDs available

KETEK

SOD SIMP DOCUMENTATION NEWS COMPANY CAREERS CONTACT

VITUS SDD Modules

VITUS H7 VITUS H20 VITUS H30 VITUS H50 VITUS H80 VITUS H90 VITUS H7L

**VITUS H20**  
30 mm<sup>2</sup> compared to 20 mm<sup>2</sup> X-ray Silicon Drift Detectors for XRF + EDX + LIBS + Applications

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PRODUCTS ORDERING INFO SOFTWARE RESOURCES NEWS & EVENTS TECHNICAL SUPPORT

FAST SDD® Ultra High Performance Silicon Drift Detector

PNDetector

Products & Applications PNDetector

# SDD Modules

Silicon Drift Detectors with superior Performance

BRUKER

PRODUCTS & SOLUTIONS APPLICATIONS SERVICES & SUPPORT

WEBINARS

## New! Windowless high collection angle EDS detector with 100% oval silicon drift detector area

ThermoFisher SCIENTIFIC

MIRION

SXD15M-150-500

Silicon Drift Detector SDD

Favorite this Product

The Mirion SDD using the proprietary spectroscopy subsystem sensitive to X-rays.

## Silicon Drift Detectors for Metallurgical Analysis

By Marlene Gasdia-Cochrane, Editor  
01.15.2015

Modern Silicon Drift Detectors (SDDs) typically outperform lithium drifted silicon, or Si(Li) detectors and have become the current state-of-the-art for high resolution, high count



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X-ray Detectors

Silicon Drift Detectors (SDD)

SSD for EDX, XRF

Single & Multi element SSD for LIBS, XRF

YOU ARE HERE: Home > X-ray Detectors > Silicon Drift Detectors (SDD) > Silicon Drift Detectors (SDD) for EDS Analysis

### SILICON DRIFT DETECTORS (SDD) FOR EDS ANALYSIS

The SiriusSDD range of Silicon Drift Detectors are designed to be compatible with all commercially available SEM and TEM systems and effortlessly interface with standard pulse processing electronics.

Although primarily an OEM product, the SiriusSDD EDS detector can also be configured as a Si(Li) replacement on most EDS user installed EDS systems.

Geometry: cylindrical

Area : 5 mm<sup>2</sup> to 150 mm<sup>2</sup>

Applications: Analysis with X-rays

FWHM <130 eV @ 5.9 keV, - 35 °C

OXFORD INSTRUMENTS NANOANALYSIS

Products Applications Learning Support

Home Products Ultim Detectors Ultim® Extreme

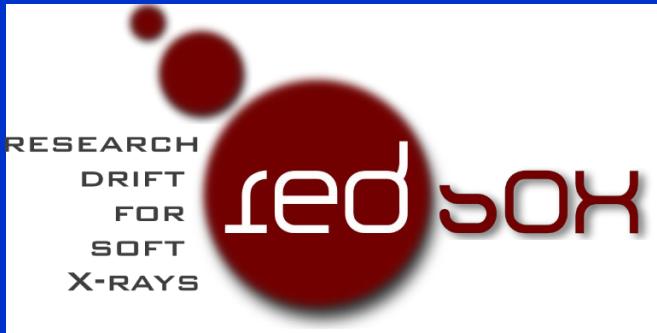
### Ultim® Extreme

Ultimate spatial resolution and low noise. Combining Extreme electronics and geometry and sensor design deliver conventional large area SDD.

# What about today SDD R&D?

## just an example...

# REDSOX: R&D collaboration on SDDs



P.I. Andrea Vacchi, University of Udine



ALMA MATER STUDIORUM  
UNIVERSITÀ DI BOLOGNA

Bologna Univ.  
G. Baldazzi



ELETTRA - Trieste  
G. Cautero



FBK - Trento  
P. Bellutti



KIT - Karlsruhe  
M. Caselle



Bologna, Roma  
C. Labanti, M. Feroci



Istituto Nazionale di Fisica Nucleare  
Bologna, Milano,  
Roma, Trento, Trieste



Università  
DI PAVIA  
Pavia University  
P. Malcovati



POLITECNICO  
MILANO 1863  
Politecnico di Milano Univ.  
G. Bertuccio



UNIVERSITÀ  
DEGLI STUDI  
DI UDINE  
hic sunt futura  
Udine University  
A. Vacchi



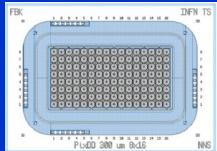
Giuseppe Bertuccio, *Semiconductor Drift Detectors: history, present and future*

23rd Workshop on Radiation Imaging Detectors - iWoRiD 2022 - Riva del Garda, Italy, 26 – 30 June 2022

slide 43

# REDSOX: a complete flow of activities

## SDD Design



INFN  
Trieste, Udine  
FBK - Trento

## ASICs Design & Test



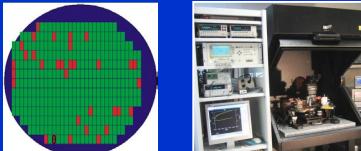
Politecnico di Milano  
University of Pavia

## SDD Manufacturing



FBK - Trento

## SDD Electrical Test



FBK, TIFPA - Trento

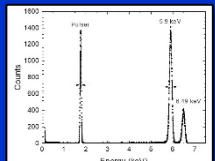
## System Assembly and Test



INAF Bologna, Roma,  
Trieste, Udine, PoliMi

## from Design to Application

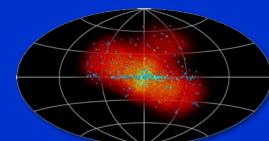
### High-End Prototypes



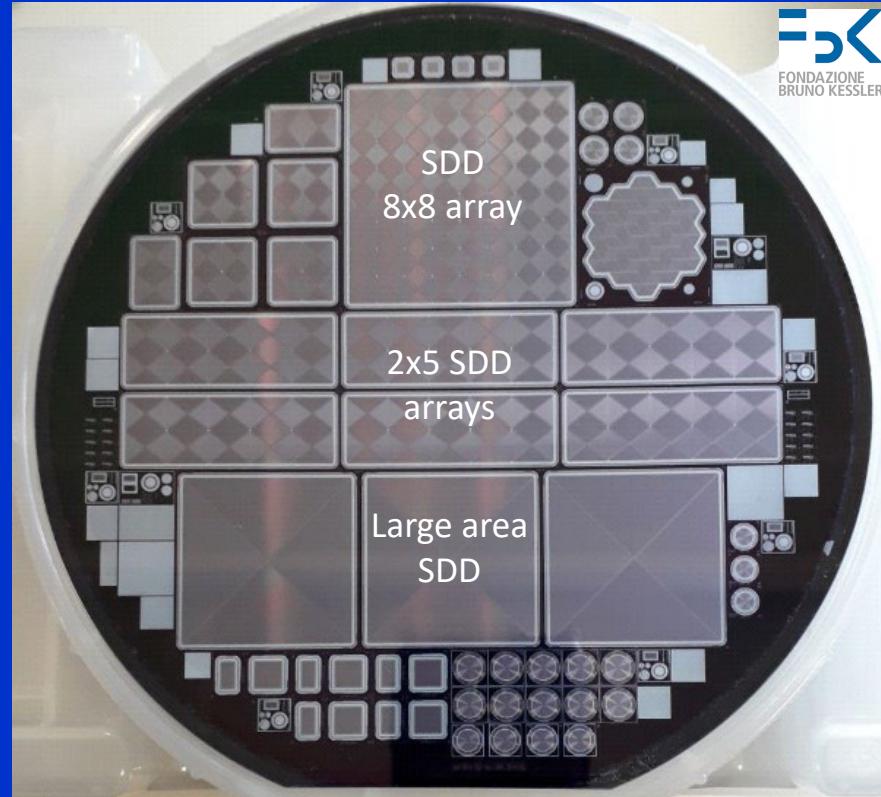
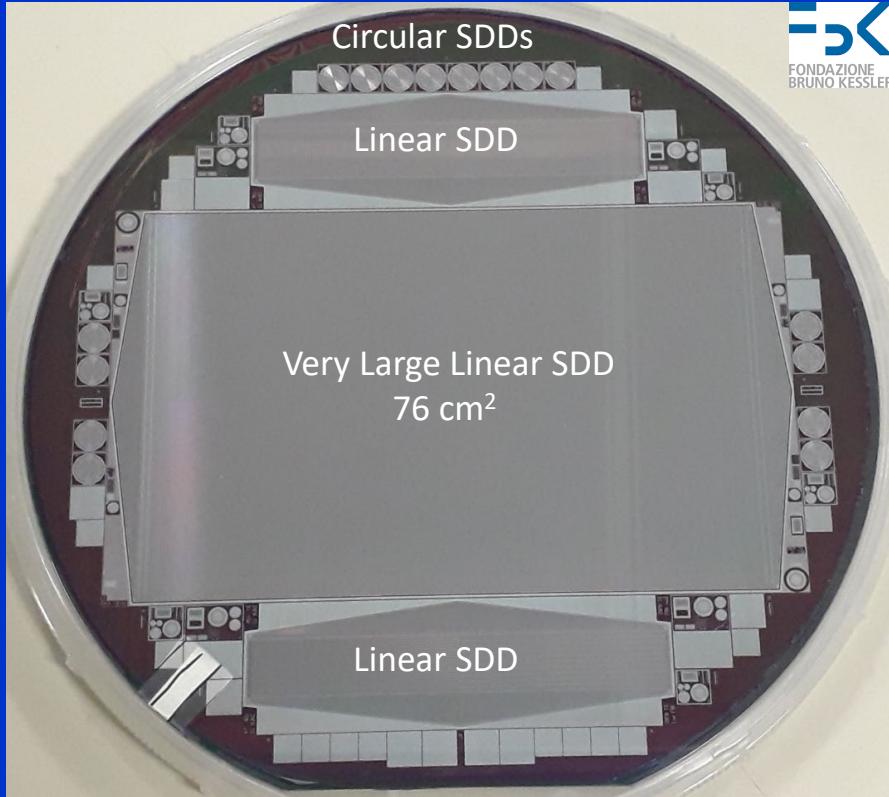
### Synchrotron System



### Space X- $\gamma$ Telescopes

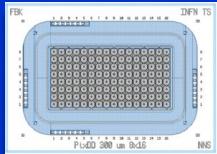


# SDD's wafers



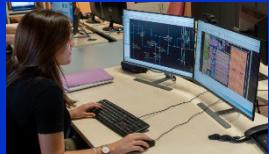
# REDSOX: a complete flow of activities

## SDD Design



INFN  
Trieste, Udine  
FBK - Trento

## ASICs Design & Test



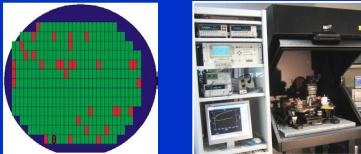
Politecnico di Milano  
University of Pavia

## SDD Manufacturing



FBK - Trento

## SDD Electrical Test

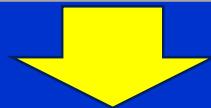


FBK, TIFPA - Trento

## System Assembly and Test

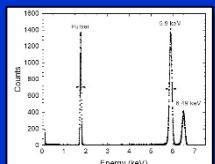


INAF Bologna, Roma,  
Trieste, Udine, PoliMi



## from Design to Application

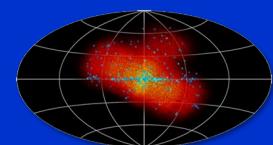
### High-End Prototypes



### Synchrotron System



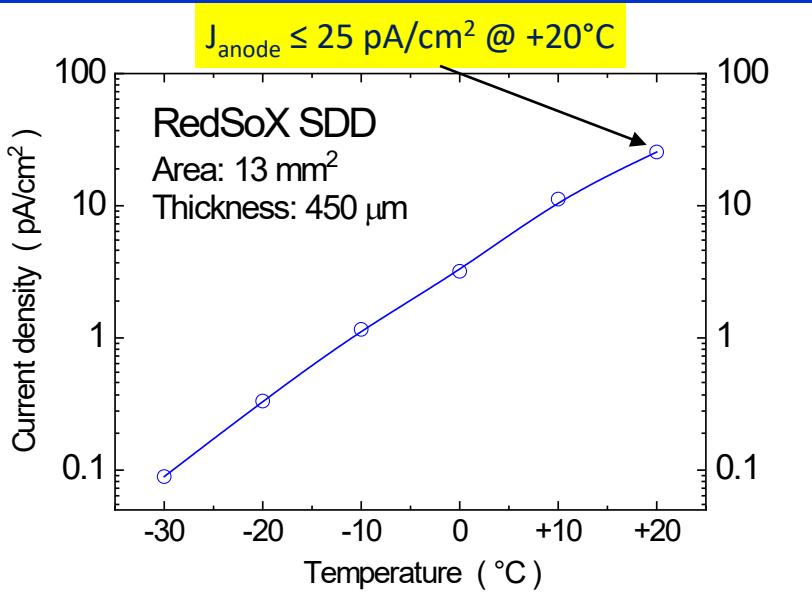
### Space X- $\gamma$ Telescopes



# Advances in SDD: ultra low anode current

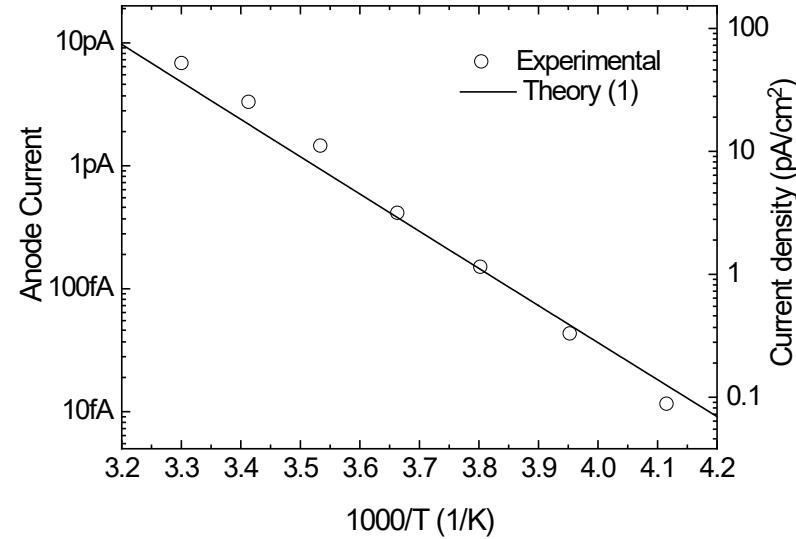
Nominal values for most processes:  $100 \div 200 \text{ pA/cm}^2$

## SDD current at anode



$$I_{\text{anode}} = AW \frac{n_i}{2\tau_o} = \frac{AW}{2\tau_o} \sqrt{N_{Co} N_{Vo}} \left( \frac{T}{T_o} \right)^{3/2} e^{-\frac{E_g}{2kT}}$$

Minority carrier lifetime:  $\tau_o = 1.16 \text{ seconds}$



# Advanced in Front-End: SIRIO Charge Preamplifier

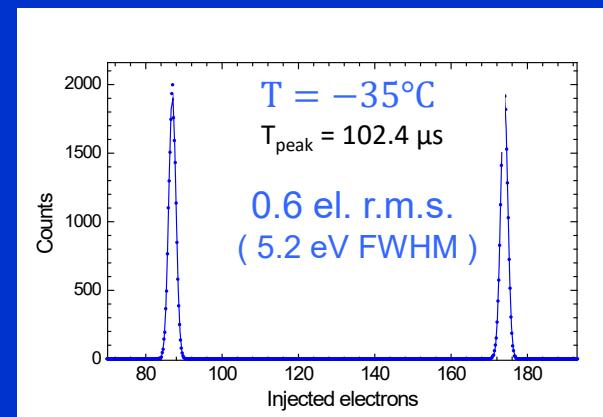
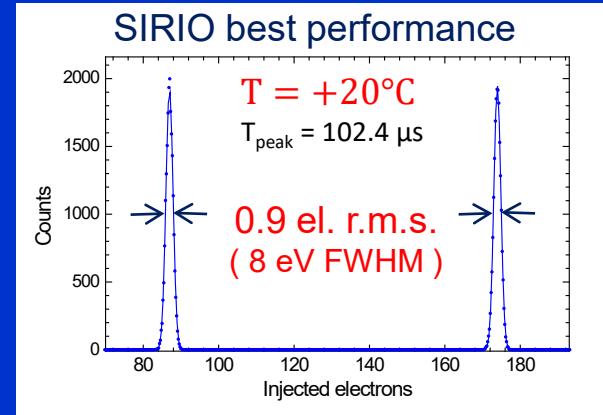
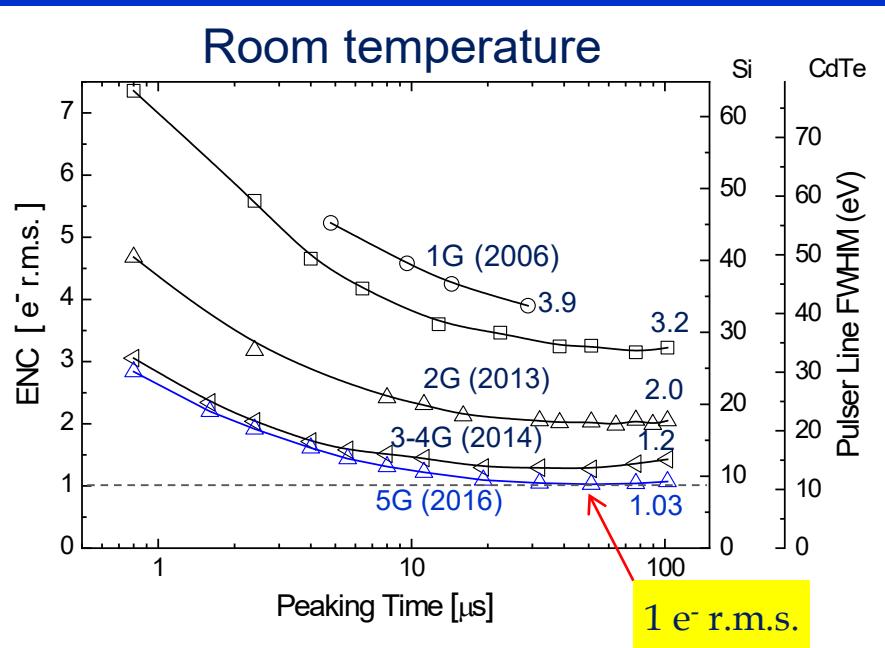
Nuclear Instruments and Methods in Physics Research A 579 (2007) 243–246

## Progress in ultra-low-noise ASICs for radiation detectors

Giuseppe Bertuccio<sup>a,b,\*</sup>, Stefano Caccia<sup>a,b</sup>

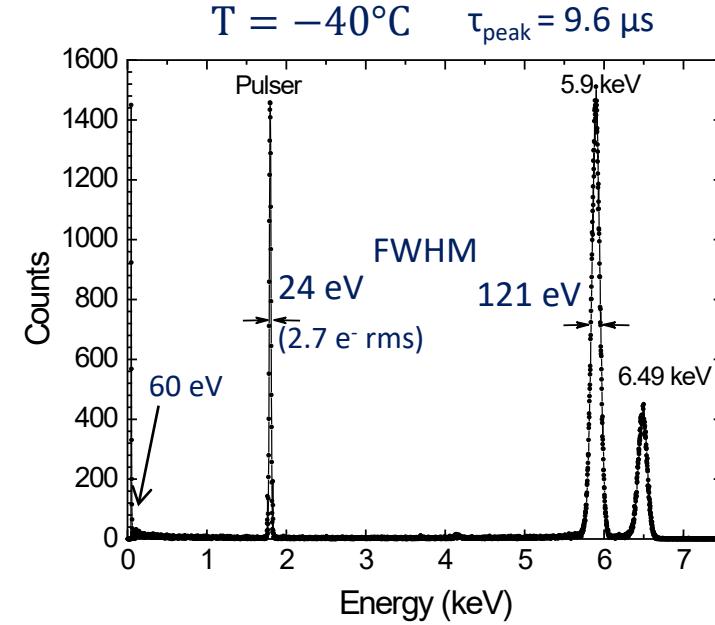
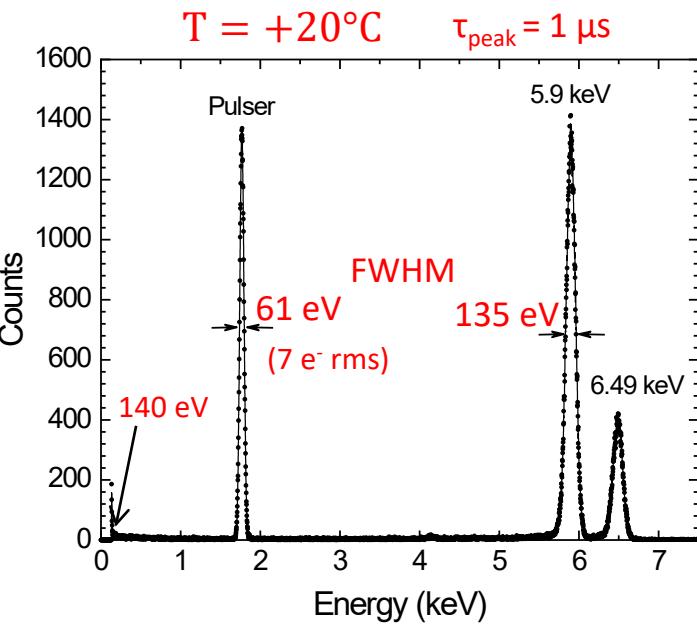
<sup>a</sup>Politecnico di Milano, Department of Electronics Engineering and Information Science, P.zza L. da Vinci 32, 20133 Milano, Italy

<sup>b</sup>National Institute of Nuclear Physics, INFN sez., Milano, Italy

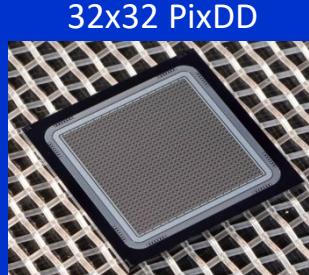
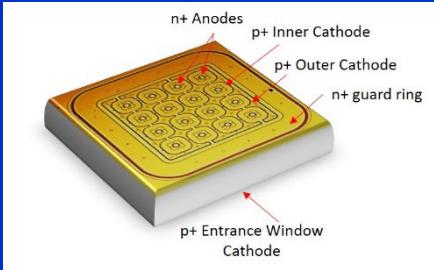


# Advances in energy resolution

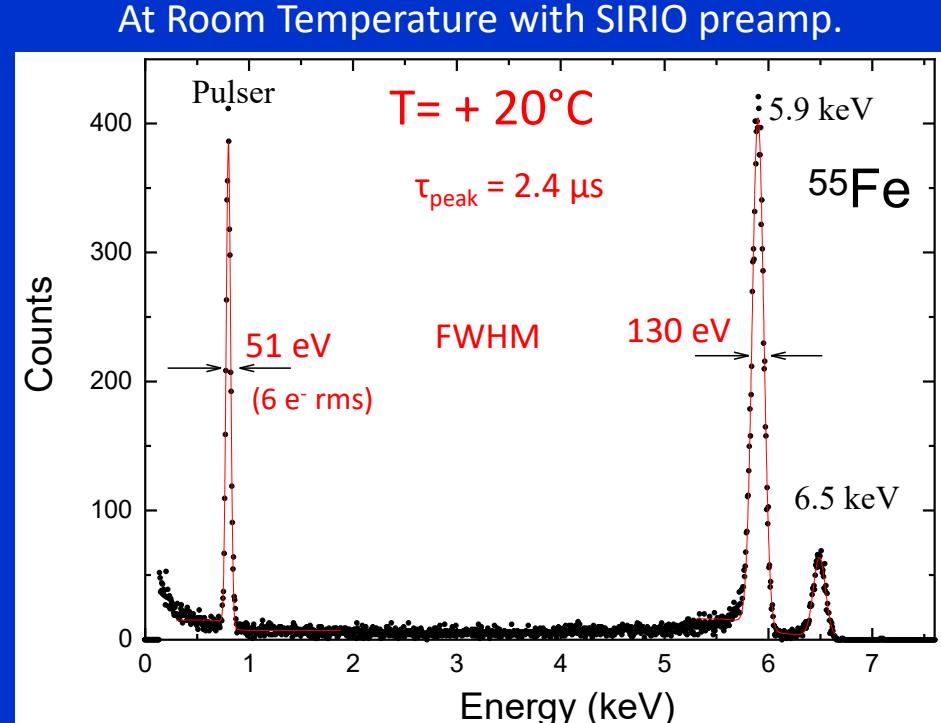
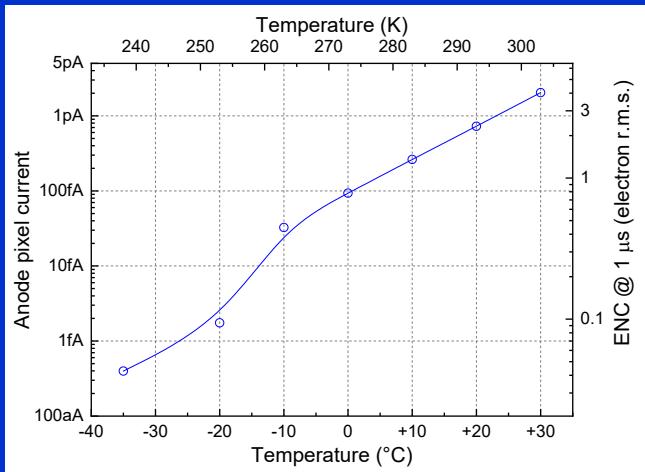
Cylindrical SDD ( $13 \text{ mm}^2$ ) coupled to SIRIO-3 Preamplifier



# PixDD: Pixel drift detector



Pixel area: 300  $\mu\text{m}$  x 300  $\mu\text{m}$



# Conventional vs. Drift Pixel

## Conventional Pixel

$I_{leakage} \leq 1 \text{ pA} @ 20^\circ\text{C}$

$C_{junction} \cong \text{tens of } fF$

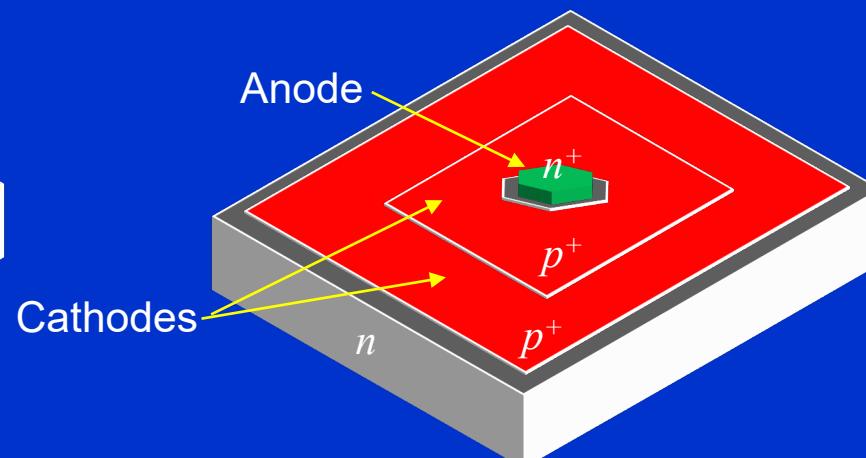
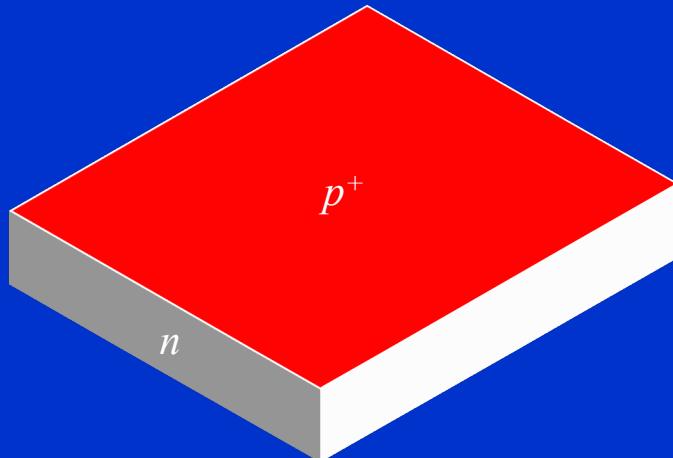
Area:  $300 \mu\text{m} \times 300 \mu\text{m}$

## Drift Pixel

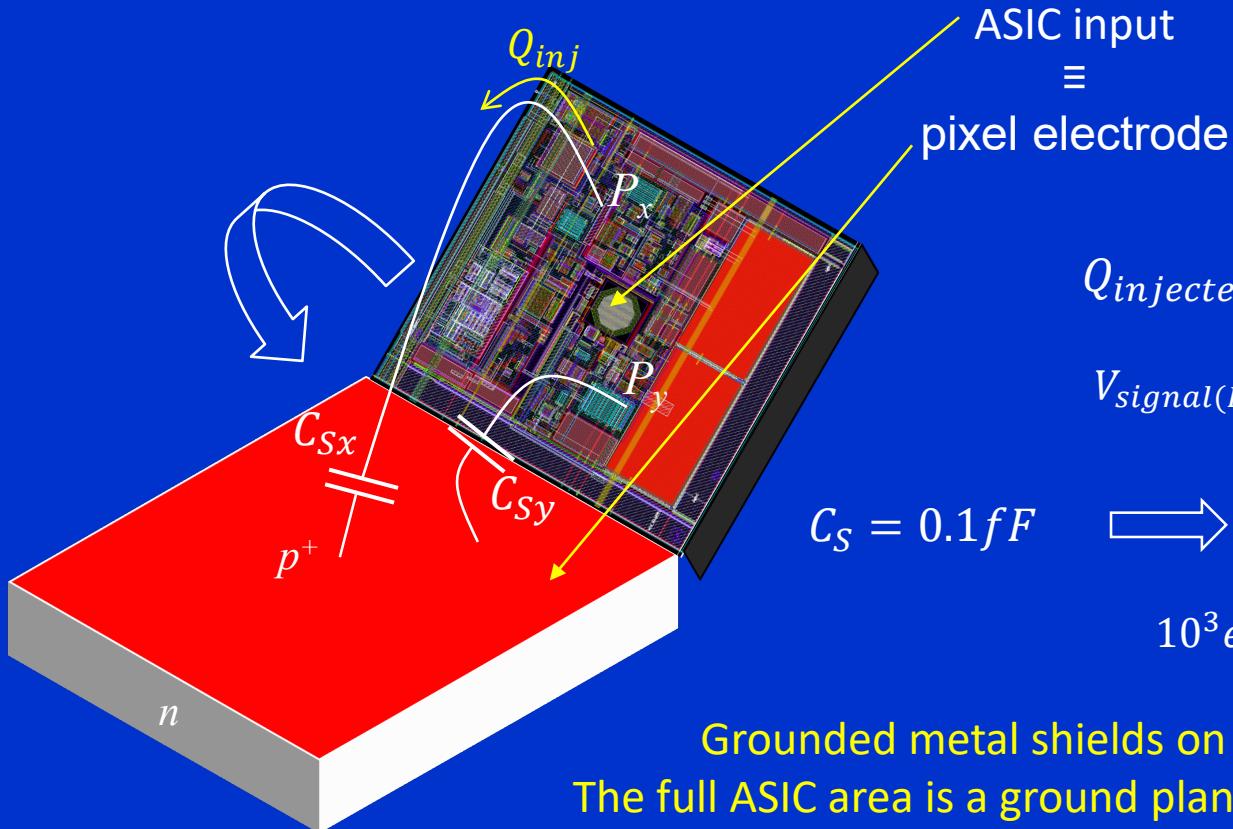
$I_{leakage} \leq 1 \text{ pA} @ 20^\circ\text{C}$

$C_{anode} \cong \text{tens of } fF$

Is there any advantage with Drift Pixels?



# Conventional Pixel



The whole pixel electrode becomes the ASIC input

$$Q_{injected(j)} = C_S j \cdot V_{signal(P_j)}$$

$V_{signal(P_j)}$ : mV to Volts

$$C_S = 0.1 fF$$

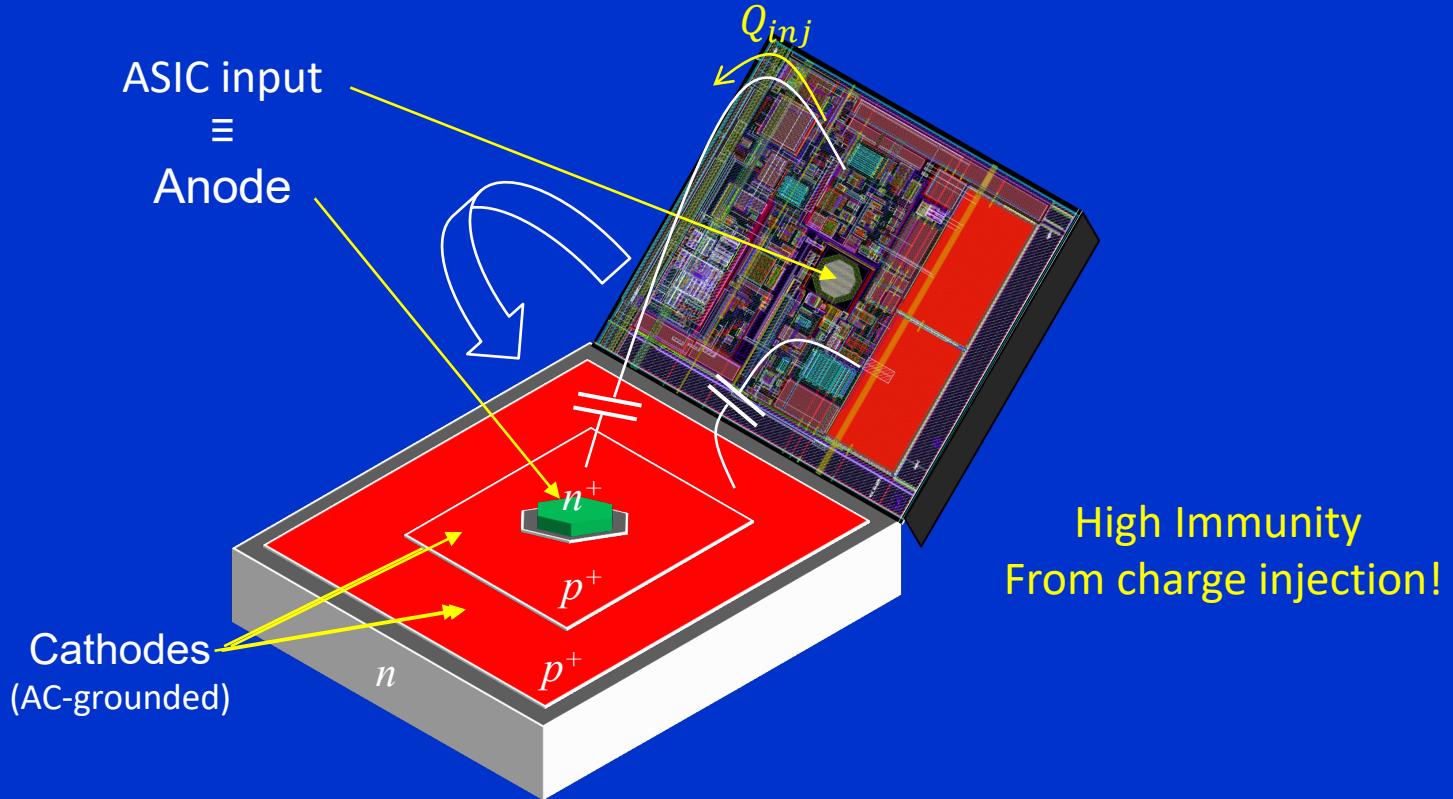
$$\implies \frac{Q_{injected(j)}}{V_{signal(P_j)}} = 10^{-16} \frac{C}{Volt}$$

$$10^3 electrons/Volt \text{ (3.6 keV/Volt)}$$

Grounded metal shields on ASIC are needed

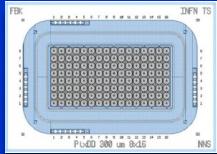
The full ASIC area is a ground plane at tens  $\mu\text{m}$  from pixel

# Drift Pixel



# REDSOX: a complete flow of activities

## SDD Design



INFN  
Trieste, Udine  
FBK - Trento

## ASICs Design & Test



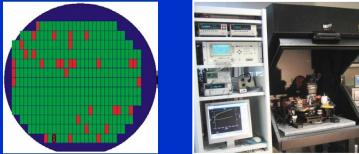
Politecnico di Milano  
University of Pavia

## SDD Manufacturing



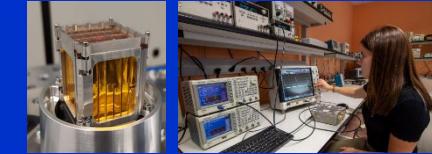
FBK - Trento

## SDD Electrical Test



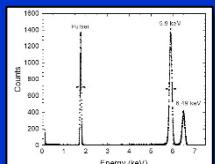
FBK, TIFPA - Trento

## System Assembly and Test



INAF Bologna, Roma,  
Trieste, Udine, PoliMi

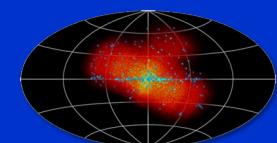
## High-End Prototypes



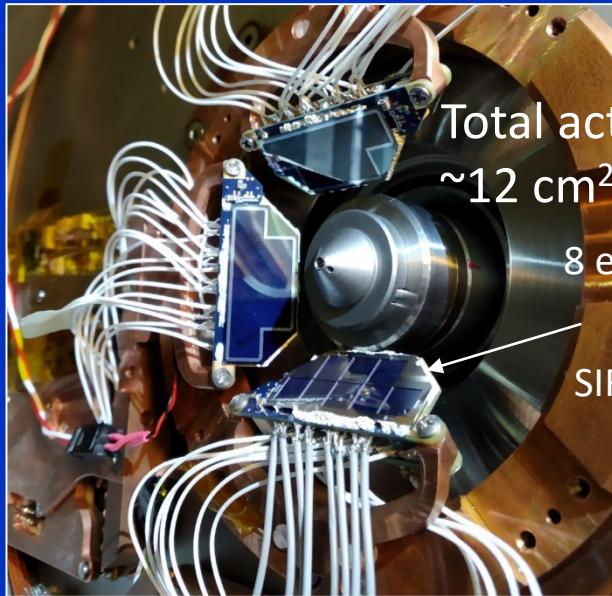
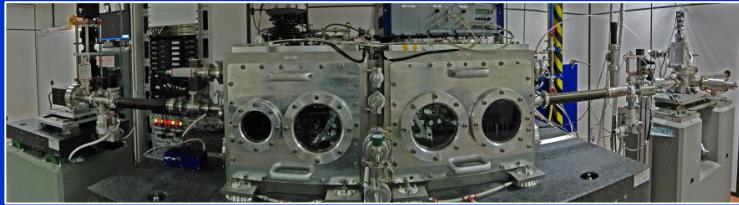
## Synchrotron System



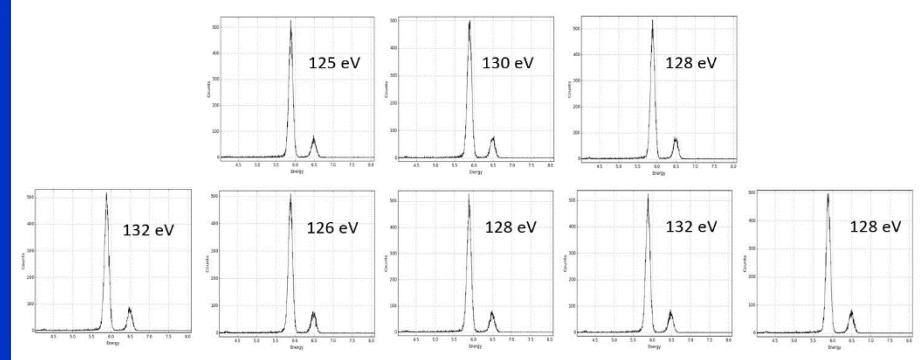
## Space X- $\gamma$ Telescopes



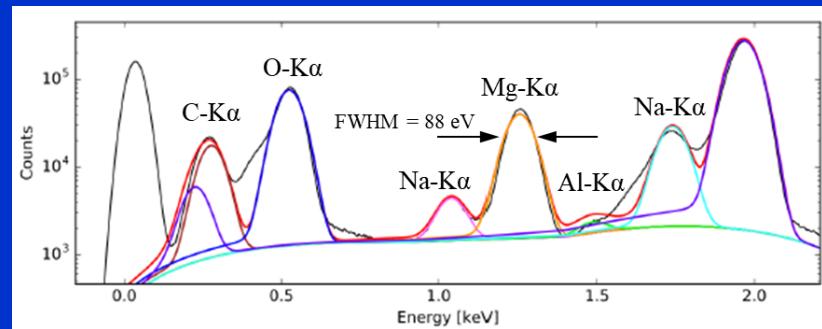
# SDDs at TwinMiC – ELETTRA Synchrotron



Best results: 125 - 132 eV FWHM @ 5.9 keV



Lightweight elements spectroscopy

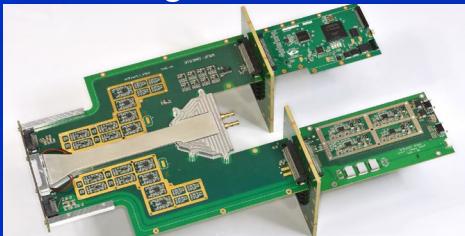


# SESAME Synchrotron (Allan, Jordan)

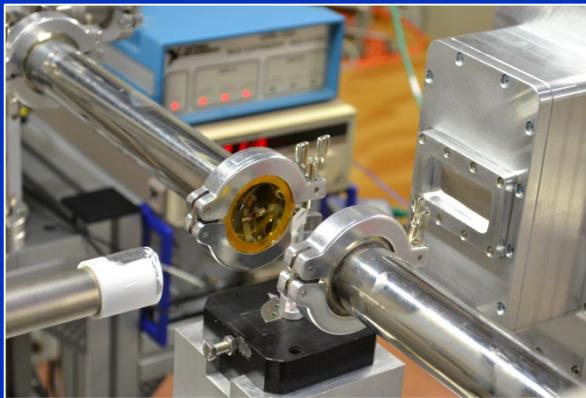
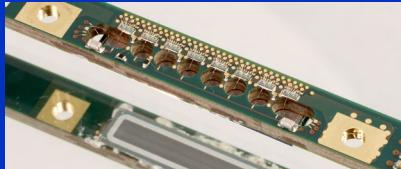
## XRF-XAFS beamline



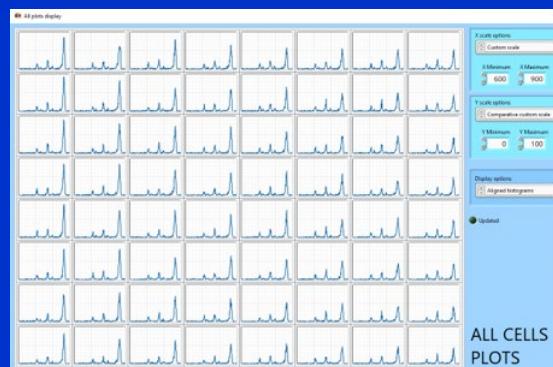
Single module



SIRIO preamp.



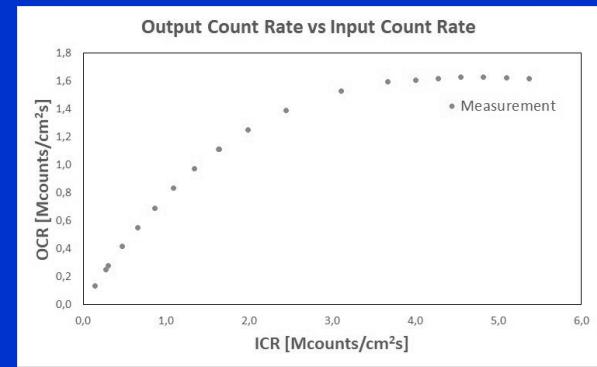
< 180 eV FWHM at 5.9 keV and +23°C



8 x 8 SDDs total area 5.7 cm<sup>2</sup>

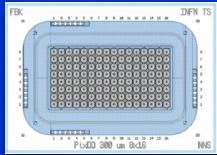


Output Count Rate: 1.6 Mcps/cm<sup>2</sup>



# REDSOX: a complete flow of activities

SDD  
Design



INFN  
Trieste, Udine  
FBK - Trento

ASICs  
Design & Test



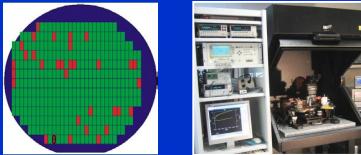
Politecnico di Milano  
University of Pavia

SDD  
Manufacturing



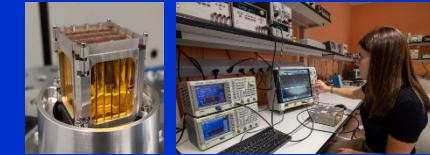
FBK - Trento

SDD  
Electrical Test



FBK, TIFPA - Trento

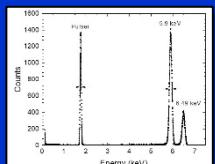
System Assembly  
and Test



INAF Bologna, Roma,  
Trieste, Udine, PoliMi

from Design to Application

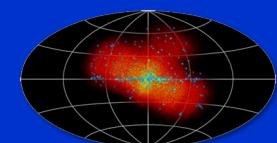
High-End Prototypes



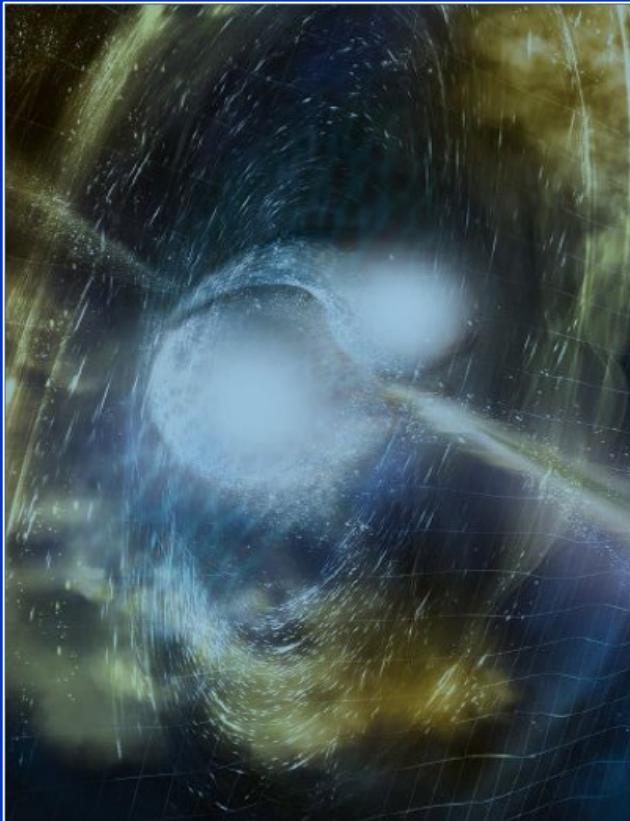
Synchrotron System



Space X- $\gamma$  Telescopes

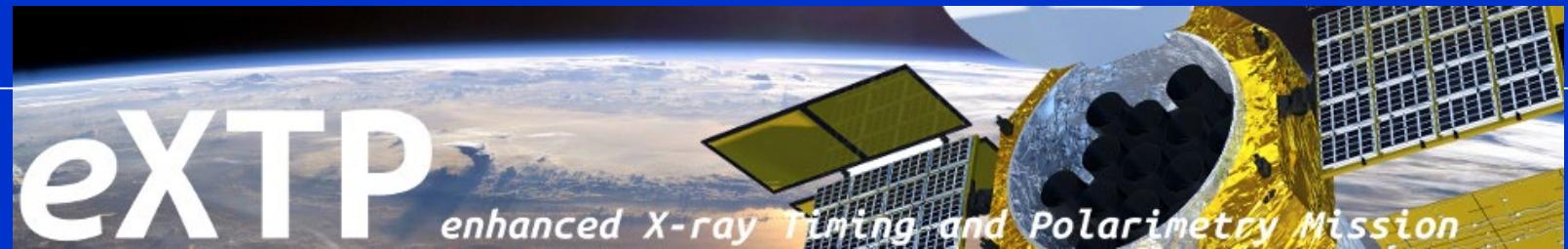


# Semiconductor Detectors for Space Telescopes



## Requirements:

- Operation on satellite
- Spectroscopic capability
- Imaging capability
- Timing capability
- Energy range: from keV to MeV
- Total sensitive area:  $> 1 \text{ m}^2$



spectral, timing and polarimetry observations

Launch date: 2027, Mission duration: 8 years

### China

P.I. Prof. Shuang Zhang  
IHEP/CAS – Beijing

CAS, CNSA, IHEP, Tsinghua Univ., Tongji Univ., CAST, Microsat



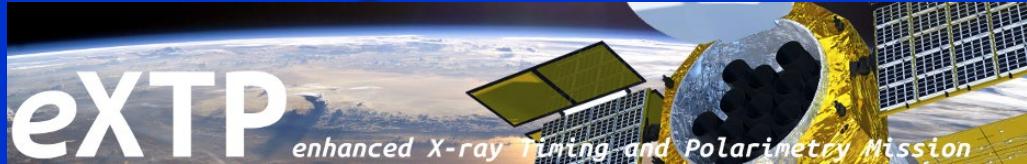
### Europe

P.I. Dr. Marco Feroci  
INAF IAPS Roma

Italy, Spain, Germany, France, Switzerland, Czech Republic, Poland, Denmark, The Netherlands, Austria, Turkey



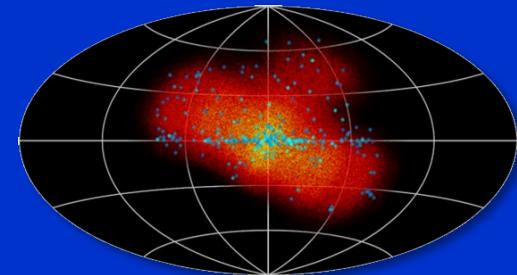
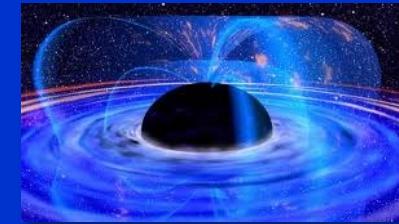
# eXTP Space Mission



Study of matter under extreme conditions of gravity, density and magnetism

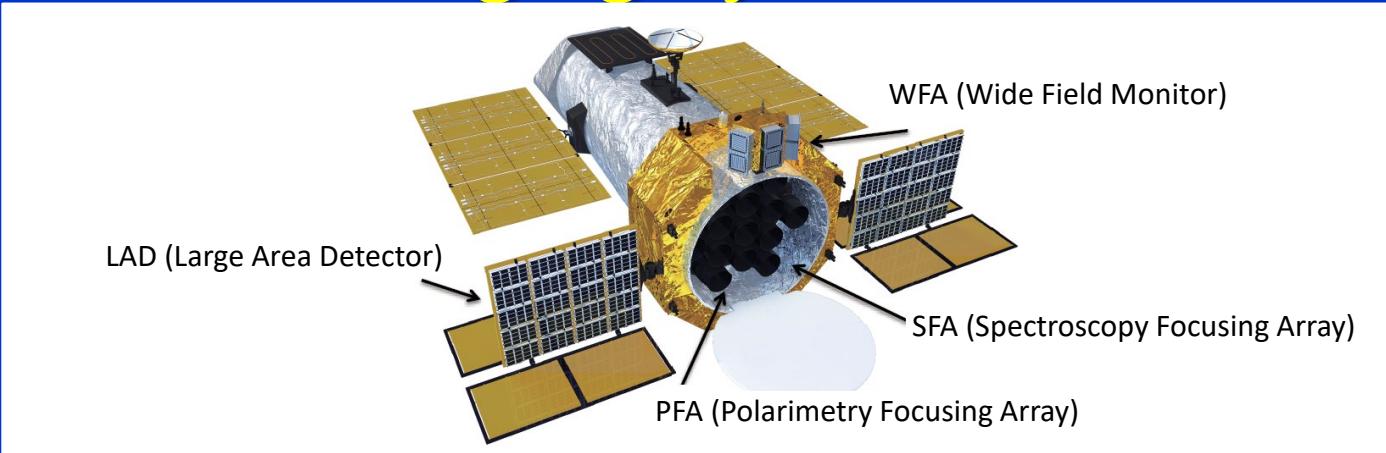
For the first time: simultaneous, high-throughput spectral, timing and polarimetry observations

- Accretion physics in the **strong-field regime of gravity** and tests of **General Relativity** in neutron stars and black holes over the mass scale.
- Physics of light and matter in the presence of **ultra-strong magnetic fields** in magnetars and X-ray pulsars.
- Multi-purpose observatory and **wide-field monitoring for transients** (and e.m. counterparts of GWs). Rapid follow-up.



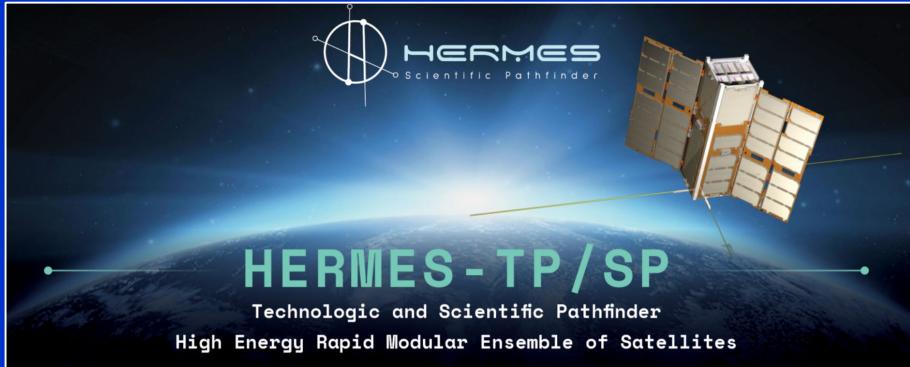
<http://www.isdc.unige.ch/extp/>

# eXTP Imaging System on satellite



Payload	Configuration	Optics	Detector	Effective Area	Energy range (keV)
SFA	9 Telescopes	Nickel replica	➡ SDD	0.5 – 0.70 m <sup>2</sup>	0.5 - 10
LAD	40 Modules	MCP Collimator	➡ SDD	3.4 m <sup>2</sup>	2 - 30
PFA	4 Telescopes	Nickel replica	Gas Pixel Detector	900 cm <sup>2</sup>	2 - 10
WFM	6 Cameras	1.5 Coded Mask	➡ SDD	FOV > 4sr	2 - 50

# Two Missions for Gamma Ray Burst Study



PI : Dr. Fabrizio Fiore

National Institute of Astrophysics (INAF)

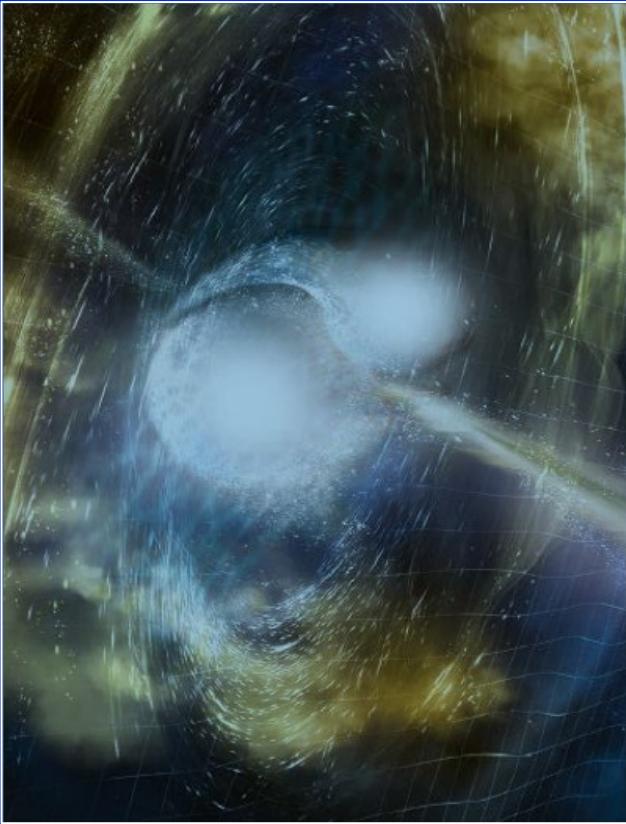
Trieste, Italy

PI : Dr. Lorenzo Amati

National Institute of Astrophysics (INAF)

Bologna, Italy

# Gamma Ray Burst (GRB)



hot topic in Astrophysics

Sudden and unpredictable burst of Soft  $\gamma$  / hard-X rays

Photon energy band: keV to MeV

Total energy:  $10^{45}$  J (  $10^{14}$  TeV)

Time duration: 0.1-100 s

Huge energy flux: up to  $1 \text{ GeV/cm}^2/\text{s}$

Extragalactic origin: neutron stars merging  
black hole formation

# HERMES project

High Energy Rapid Modular Ensemble of Satellites

PI : Dr. Fabrizio Fiore - INAF-OATS, Trieste, Italy

Scientific goal: Gamma-Ray Burst study

- localization (arc-min accuracy)
- timing ( $\mu$ s resolution)

Detection apparatus: 3U CubeSats

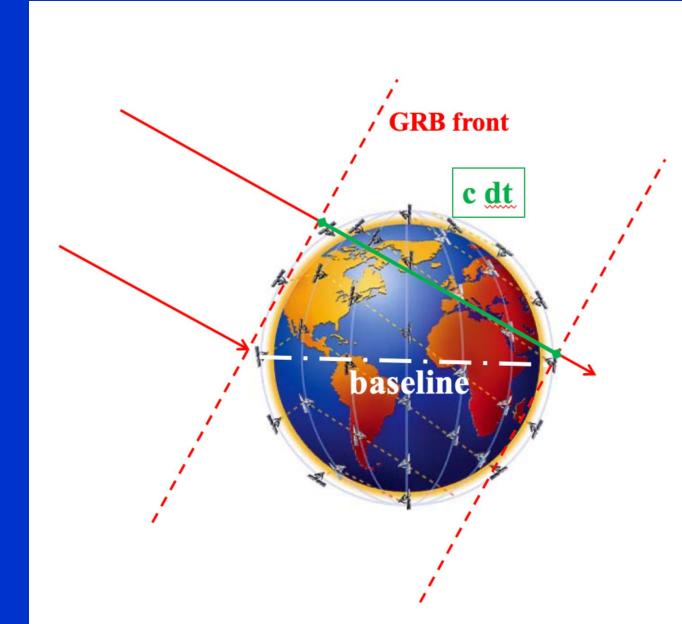
Orbit: equatorial 525 km altitude

Detectors: Scintillators (GAGG:Ce) + SDDs

GRB localization: triangulation

Launch: first 6 CubeSats in 2023

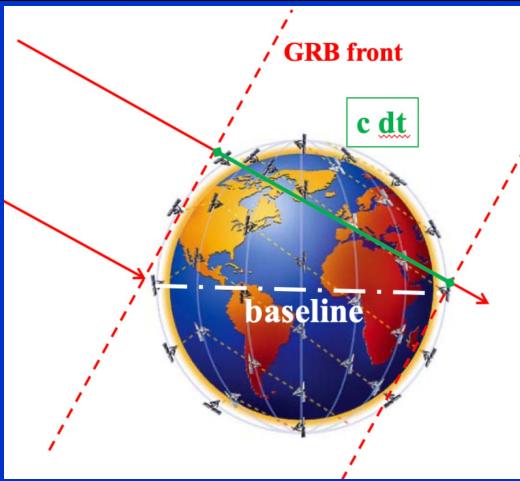
Peculiarities: modularity, all sky coverage, low cost





# HERMES-TP/SP

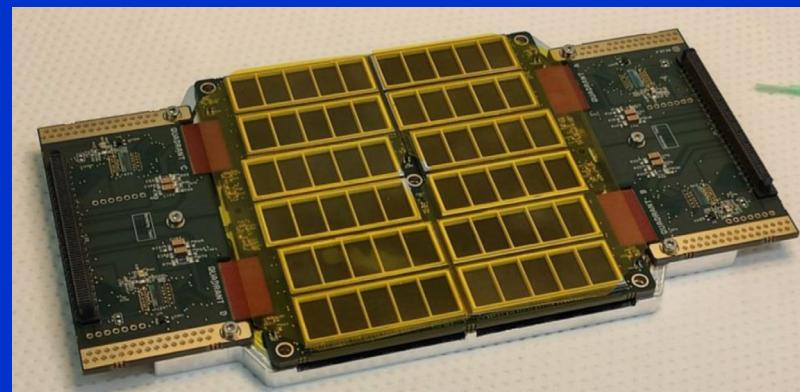
Technologic and Scientific Pathfinder  
High Energy Rapid Modular Ensemble of Satellites



Cubesat  
for GRB localization

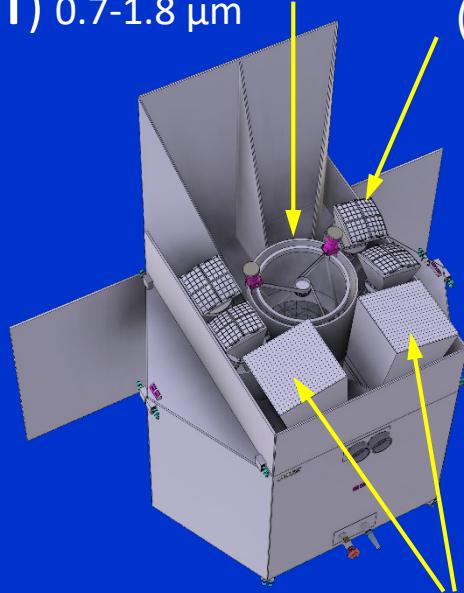


CubeSat 3U  
10 x 10 x 30 cm<sup>3</sup>



Energy band: 50 – 300 keV  
60 GAGG read by 2 SDDs  
120 SDDs organized in 12 arrays (53 cm<sup>2</sup>)  
Array: 2x5 SDDs 7.4x6 mm<sup>2</sup> (4.4 cm<sup>2</sup>)

InfraRed Telescope  
(IRT) 0.7-1.8  $\mu$ m



4x Soft X-ray Imagers  
(SXI) 300 eV – 5 keV

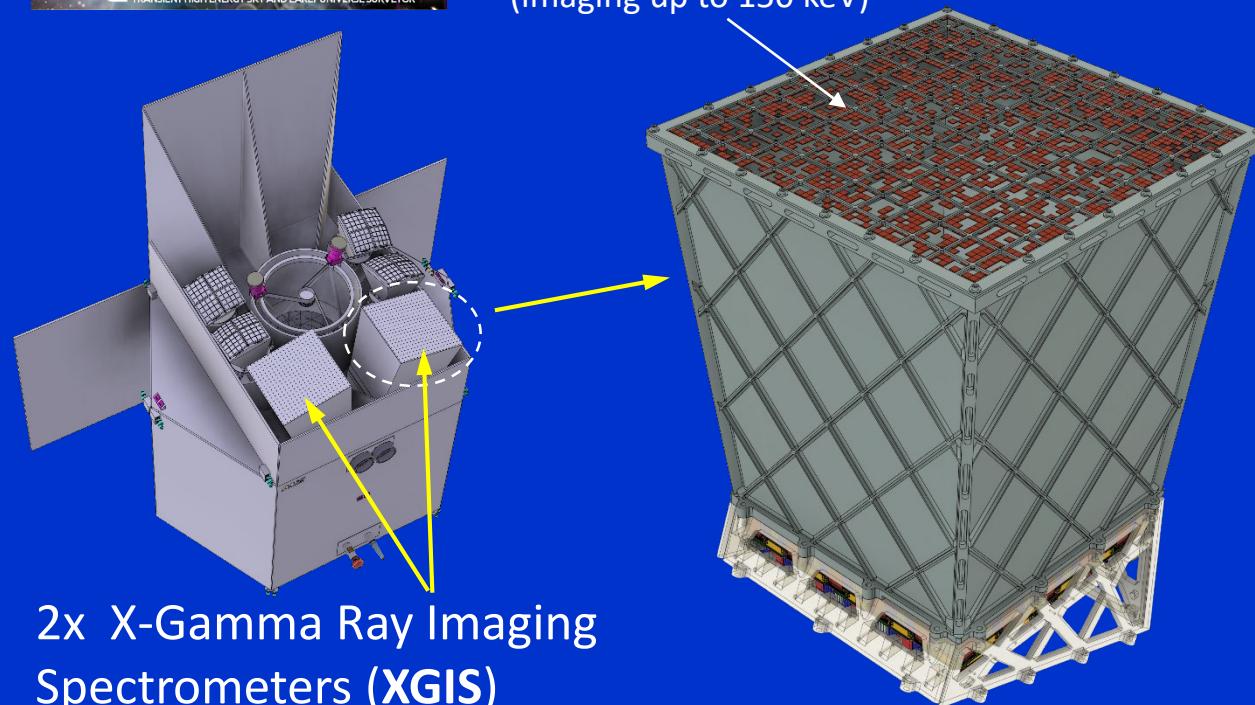


2x X-Gamma Ray Imaging  
Spectrometers (XGIS)  
2 keV – 10 MeV

# THESEUS: the X-Gamma Ray Imaging Spectrometer

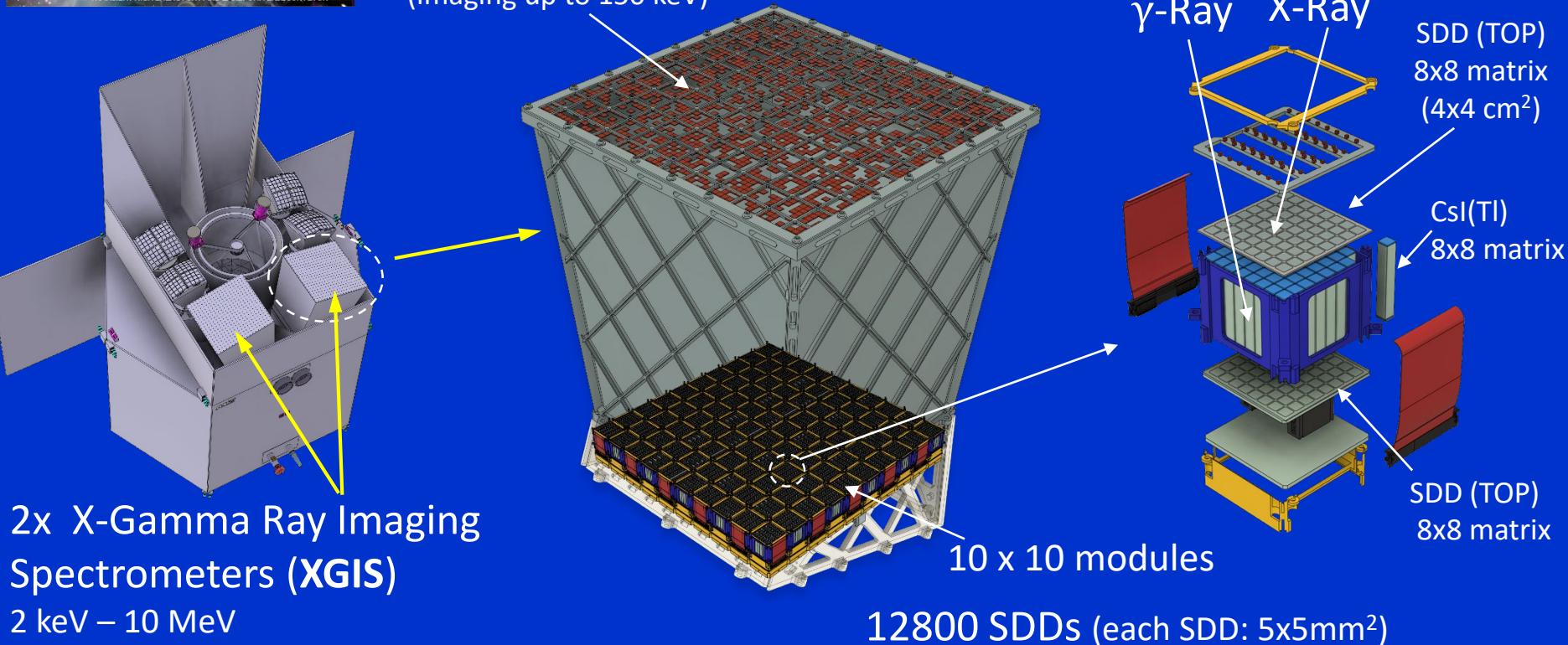


Coded mask (60x 60 cm<sup>2</sup>)  
(imaging up to 150 keV)



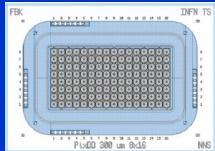
2x X-Gamma Ray Imaging  
Spectrometers (**XGIS**)  
2 keV – 10 MeV

# THESEUS: the X-Gamma Ray Imaging Spectrometer



# REDSOX: a complete flow of activities

## SDD Design



INFN  
Trieste, Udine  
FBK - Trento

## ASICs Design & Test



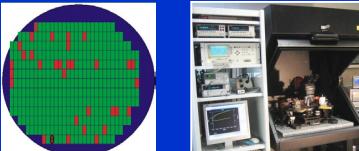
Politecnico di Milano  
University of Pavia

## SDD Manufacturing



FBK - Trento

## SDD Electrical Test



FBK, TIFPA - Trento

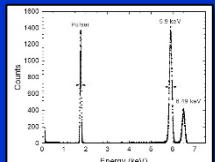
## System Assembly and Test



INAF Bologna, Roma,  
Trieste, Udine, PoliMi

## from Design to Application

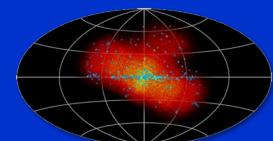
### High-End Prototypes

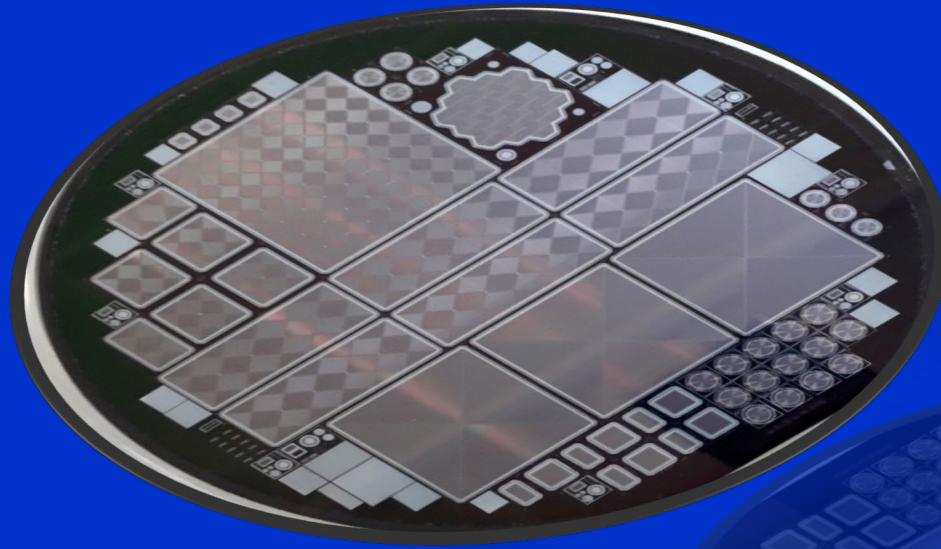


### Synchrotron System



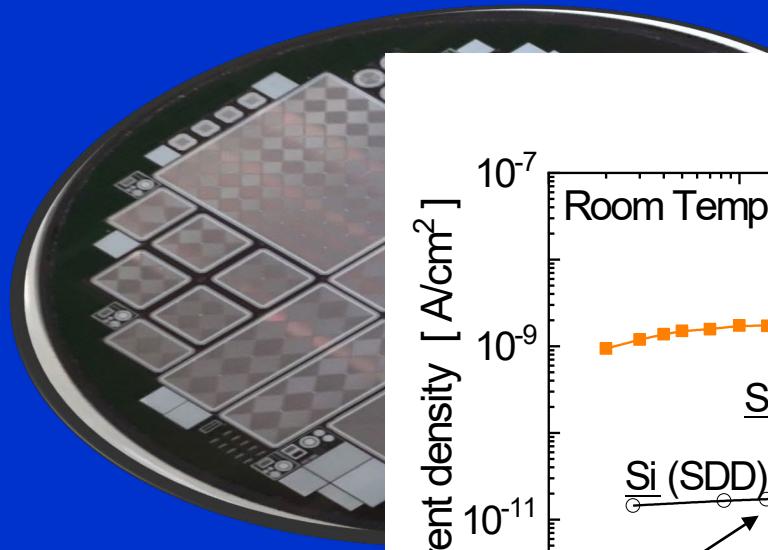
### Space X- $\gamma$ Telescopes



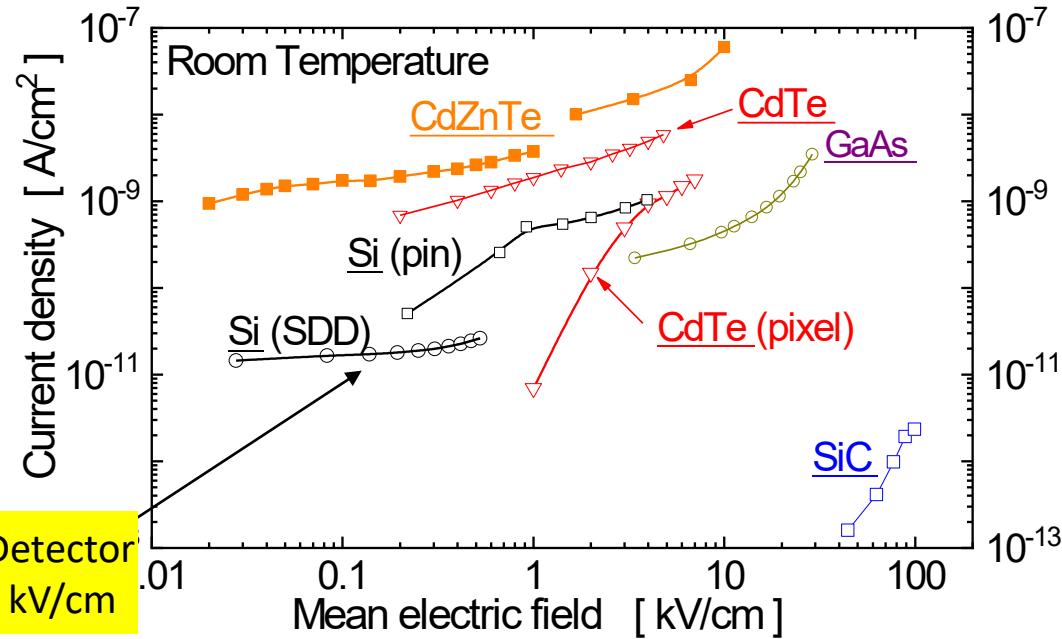


# SDD's future where to go? what we should expect?

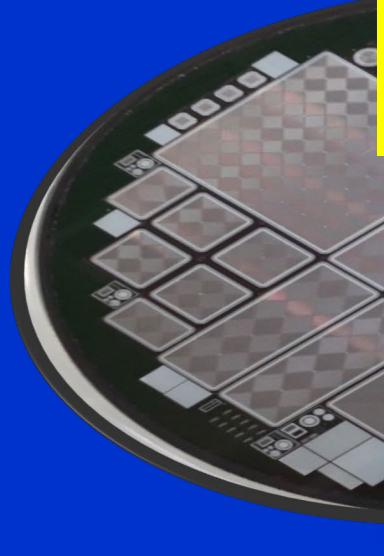
# Ultra low noise SDD



Best Silicon Drift Detector  
25 pA/cm<sup>2</sup> @ 0.5 kV/cm



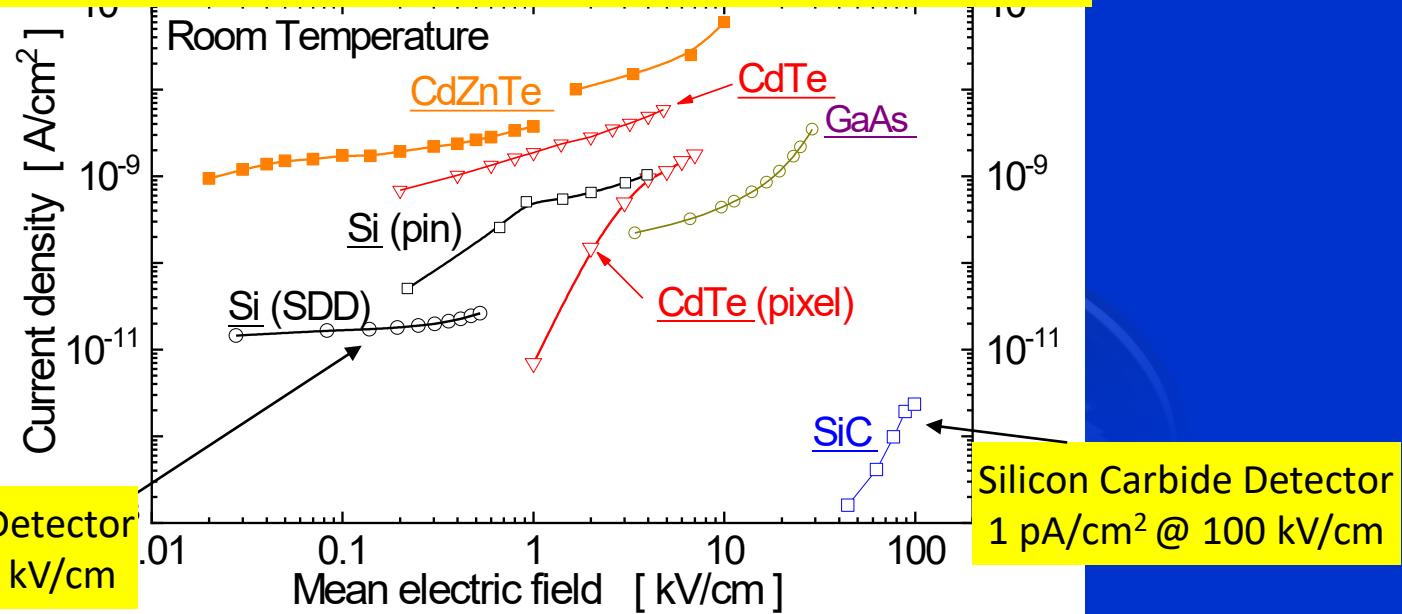
# Ultra low noise SDD



## SiC Drift Detectors

Ultra low noise (low  $I_{DET}$ , low  $C_{DET}$ )

Ultra Fast (operation close to electron saturation velocity)



# Conclusion

Solid State Drift Detectors  
a great idea...  
a fascinating story...  
a still amazing adventure...

Thanks to Emilio Gatti and Pavel Rehak  
and to each one who is continuing their passion

